

Authenticache: Harnessing Cache ECC for System Authentication

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THE OHIO STATE UNIVERSITY

COMPUTER
ARCHITECTURE
RESEARCH LAB





Security and Everyday Computing



Security is now crucial to all computing markets, especially with the advent of IoT





Security Challenges



Security Challenges

- Password management
- Complexity due to different accounts having policies





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 - Complexity due to different accounts having policies
- Secure key storage
 - Increases complexity for low cost IoT devices





Security Challenges

- Password management
 - Complexity due to different accounts having policies
- Secure key storage
 - Increases complexity for low cost IoT devices
- Software as a Service
 - Personal device at workplace increasing security risks

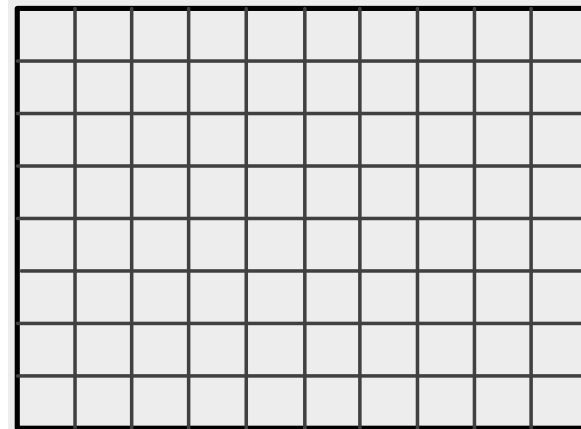




Physical Unclonable Functions (PUF)



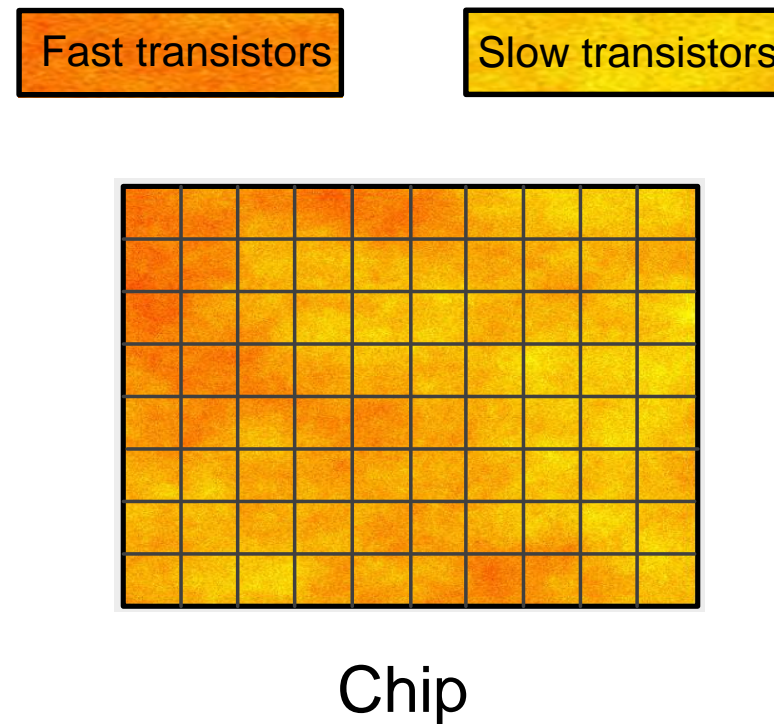
Physical Unclonable Functions (PUF)



Chip



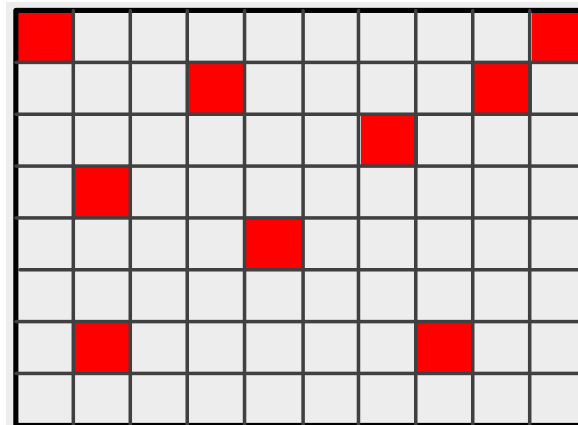
Physical Unclonable Functions (PUF)



- Exploit randomness in silicon



Physical Unclonable Functions (PUF)



Chip

Silicon Fingerprints

- Exploit randomness in silicon
- Systematic outputs unique to device

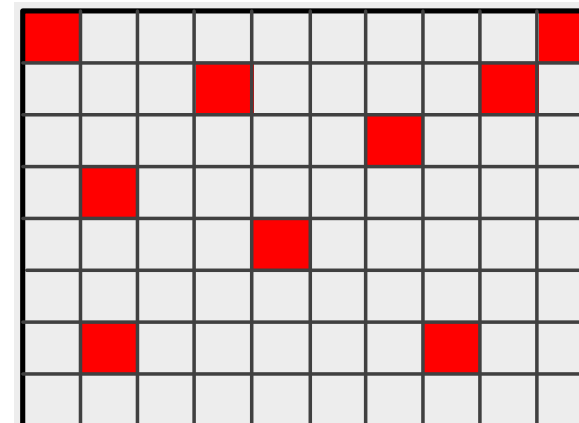
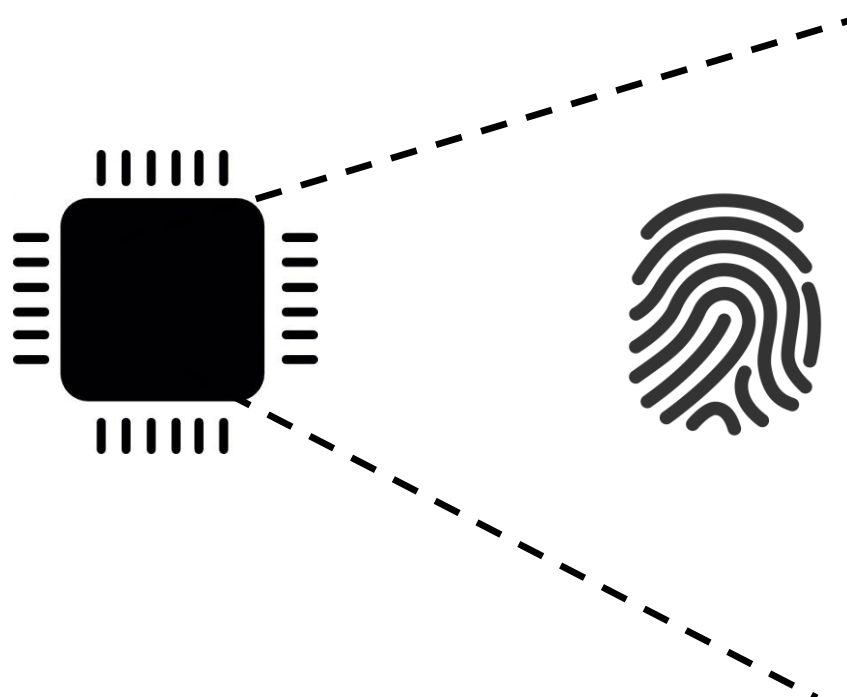
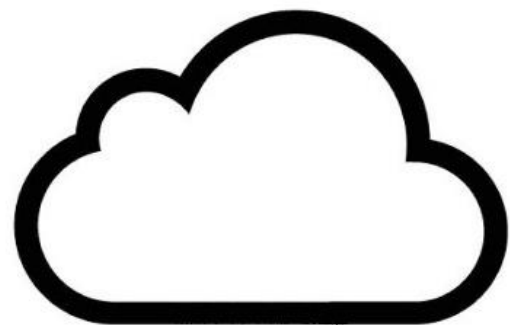


PUF System Authentication



PUF System Authentication

Enrollment

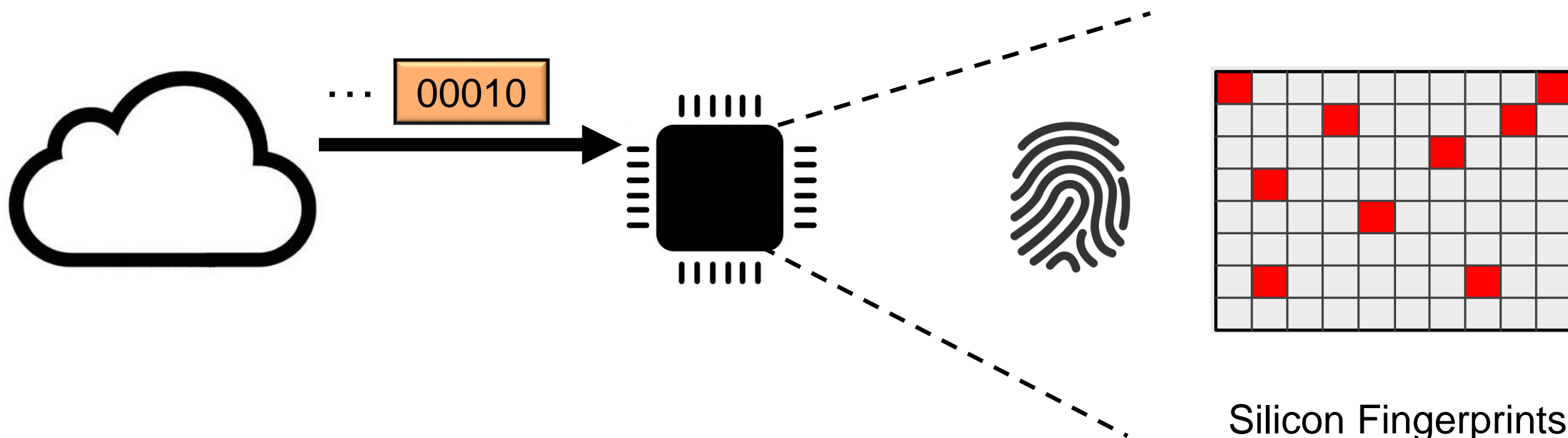


Silicon Fingerprints



PUF System Authentication

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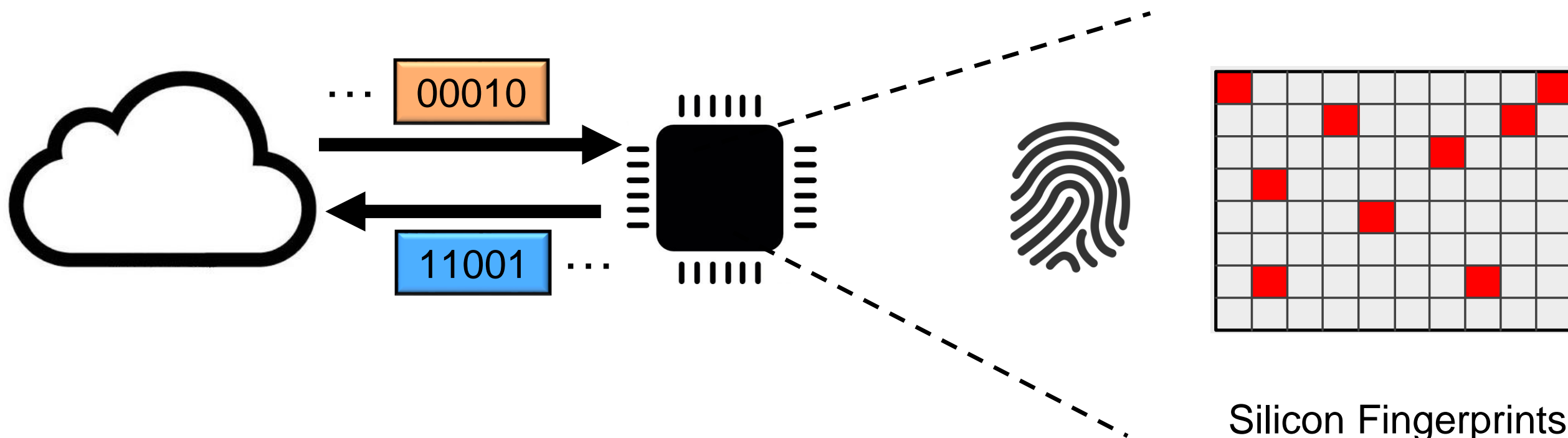


Silicon Fingerprints



PUF System Authentication

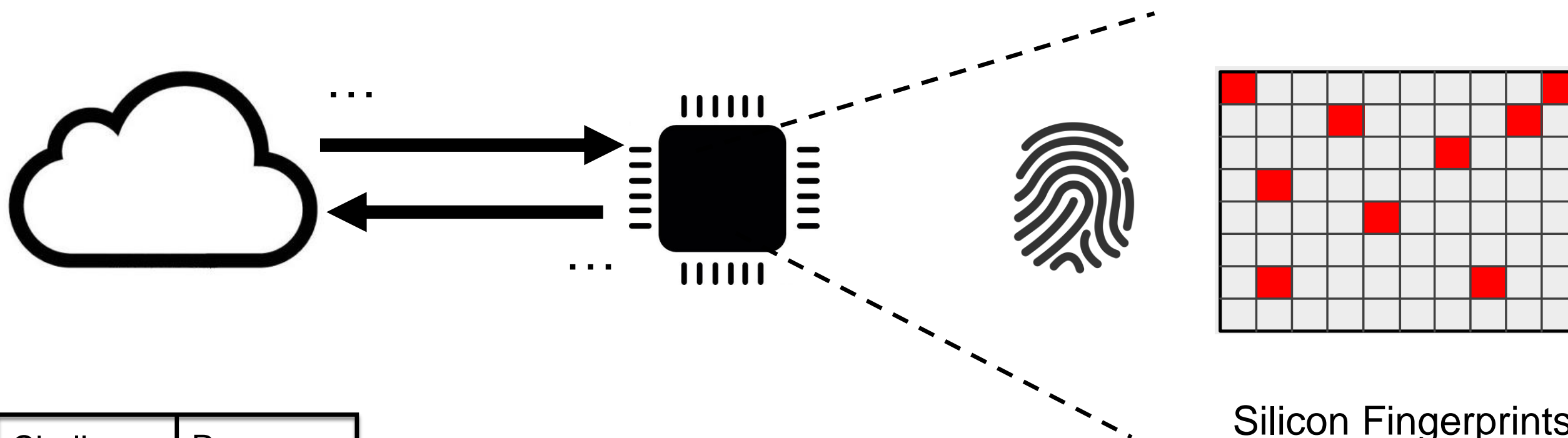
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PUF System Authentication

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Silicon Fingerprints

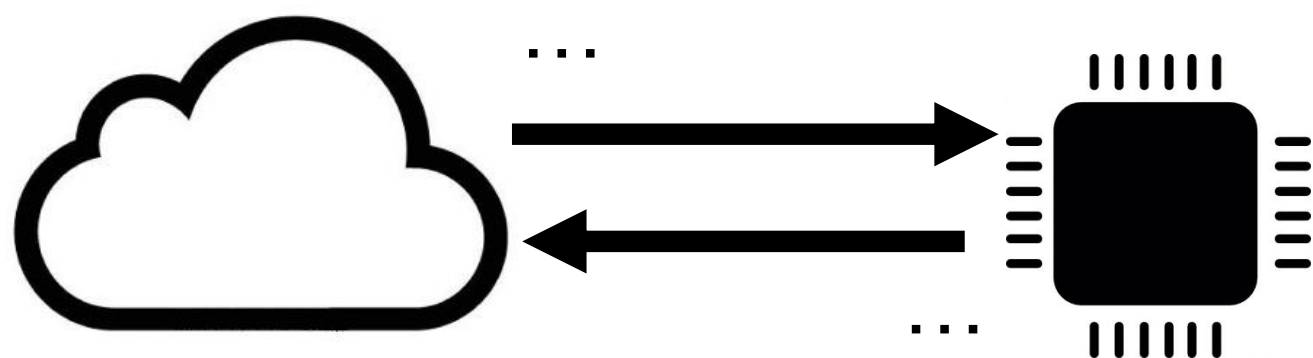
Challenge	Response
01100	00110
...	...
00010	11001



PUF System Authentication

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Authentication



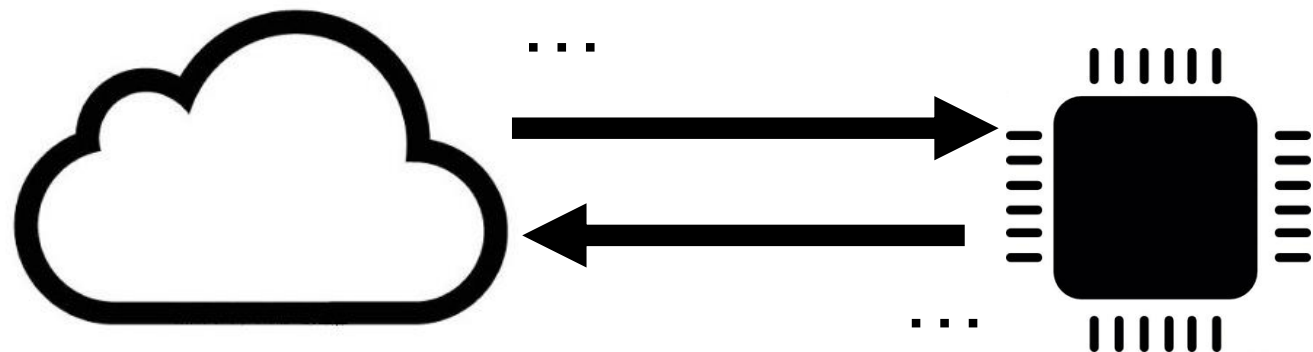
Challenge	Response
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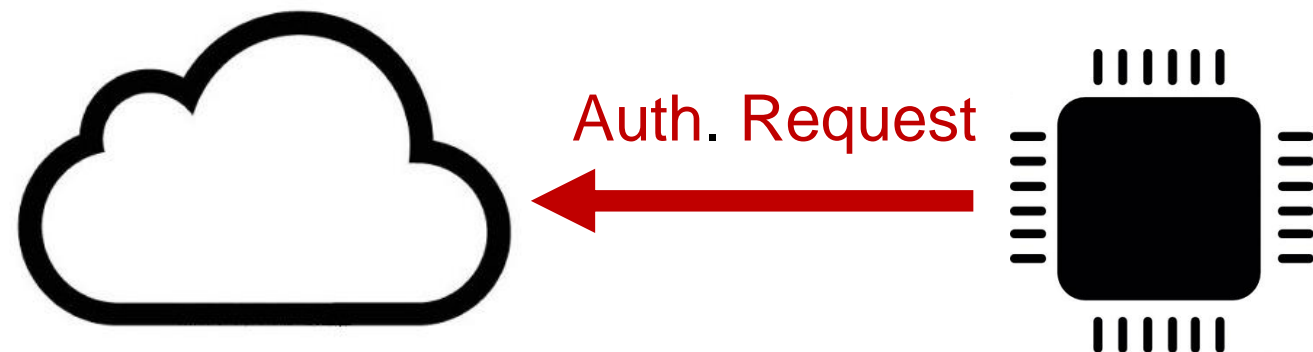


PUF System Authentication

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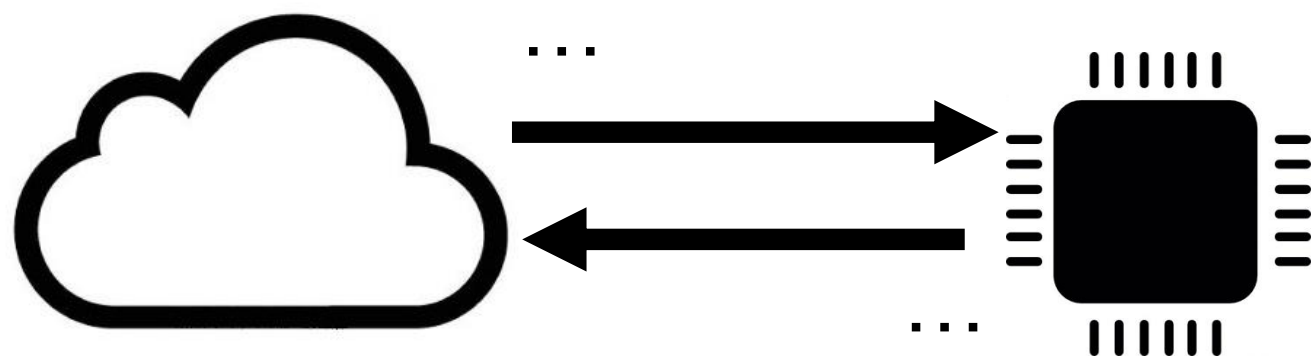
Challenge	Response
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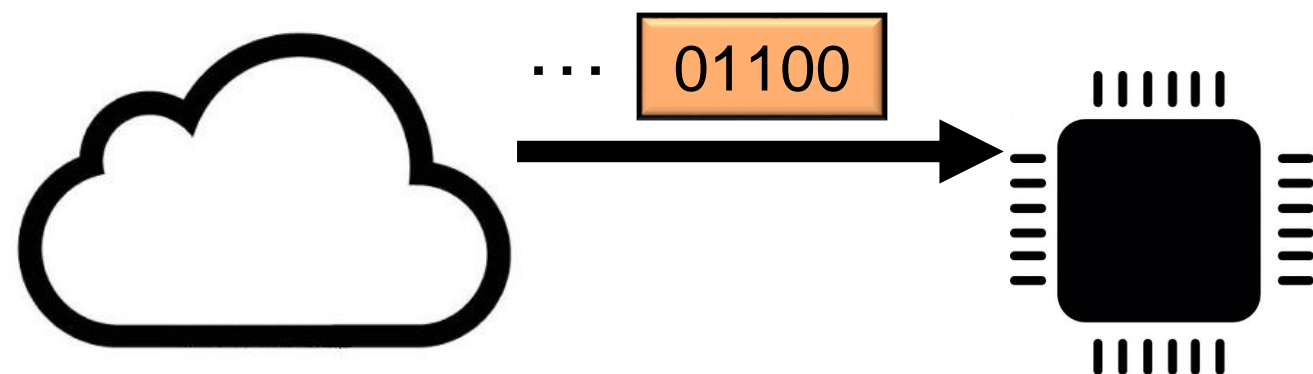


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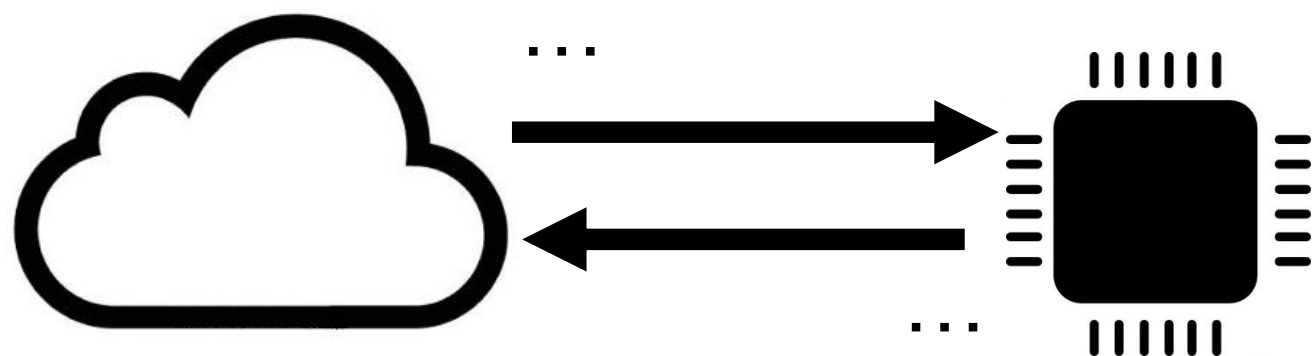
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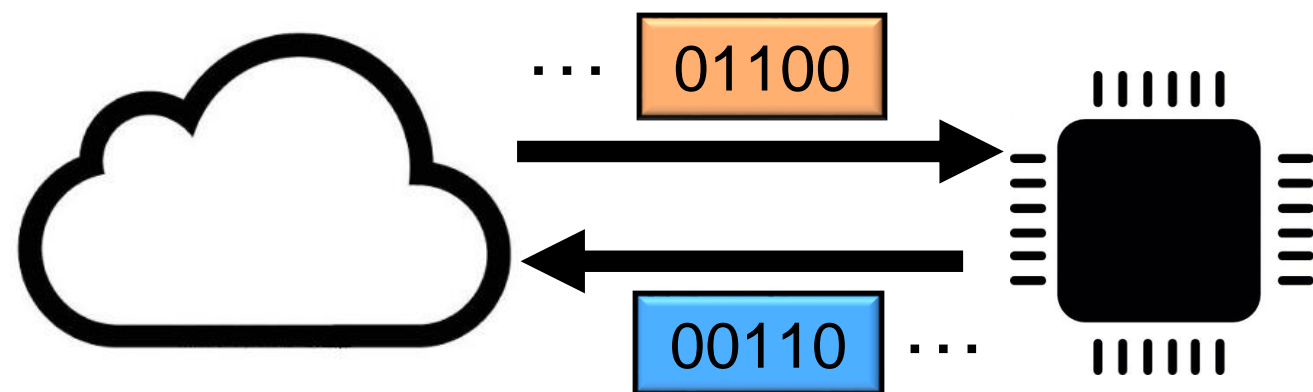


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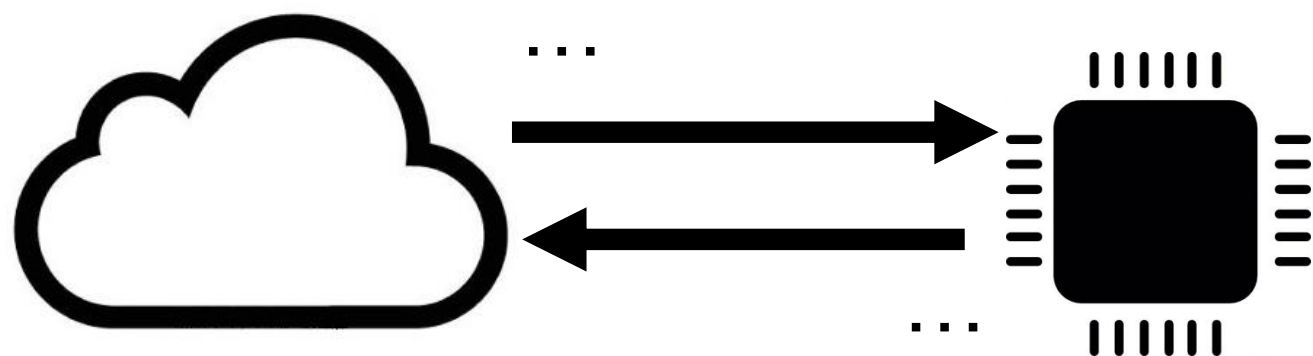
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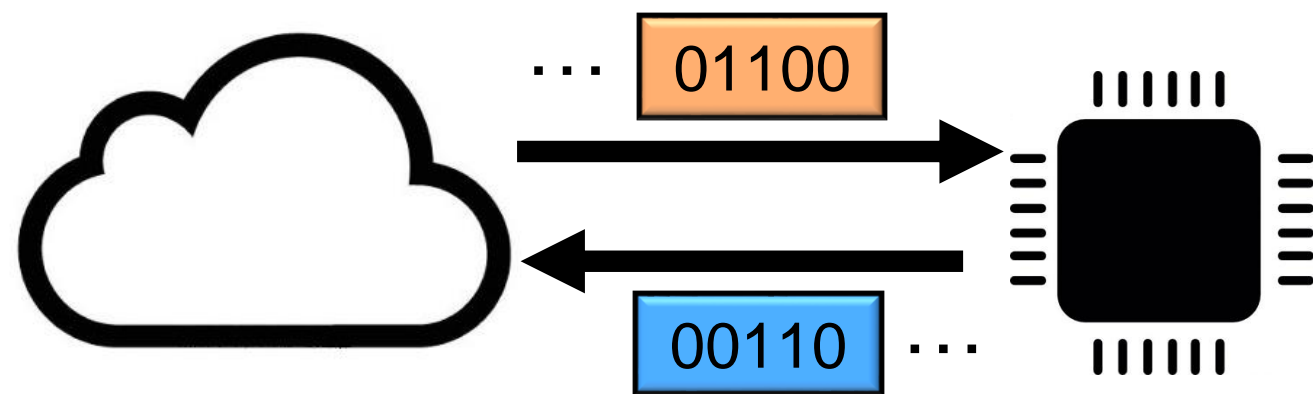


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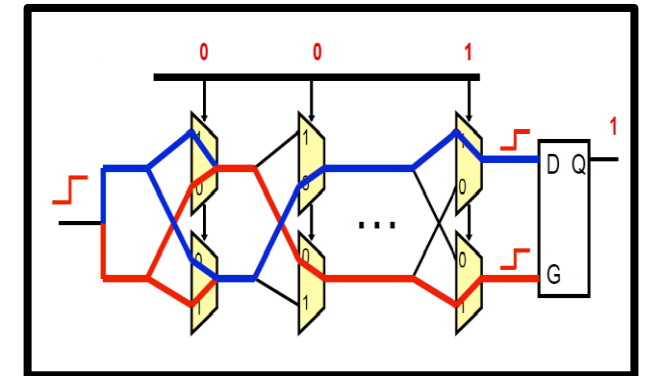


Related Work



Related Work

- Arbiter PUF (Lee et al. VLSI'04)
- Signal traversing maze of cascaded switch blocks

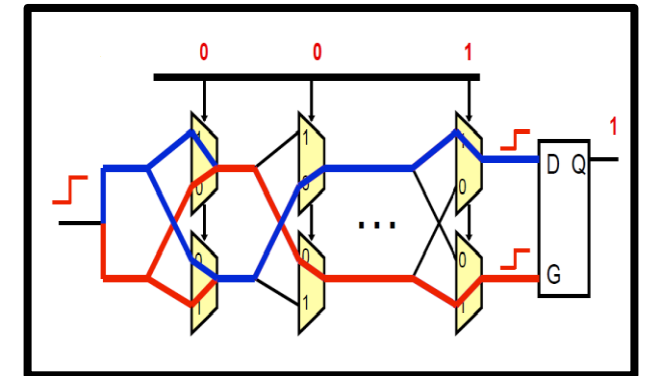


Arbiter PUF

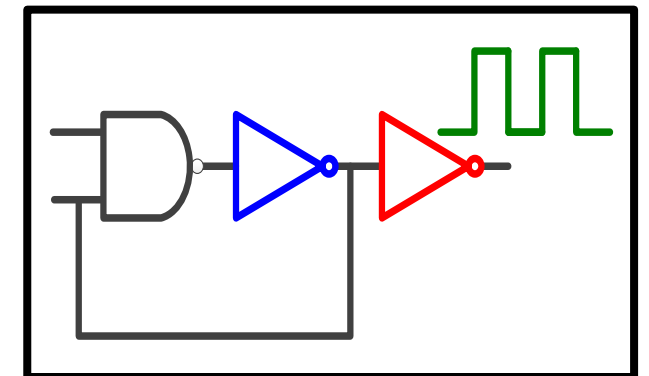


Related Work

- Arbiter PUF (Lee et al. VLSI'04)
- Signal traversing maze of cascaded switch blocks
- Ring Oscillator PUF (Suh et al. DAC'07)
- Delay loops feeding oscillations into counters



Arbiter PUF

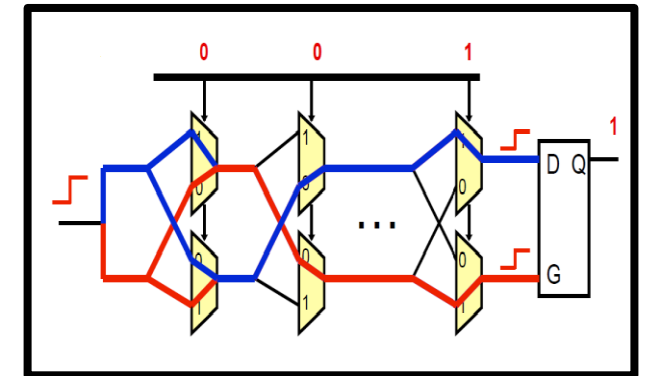


Ring Oscillator PUF

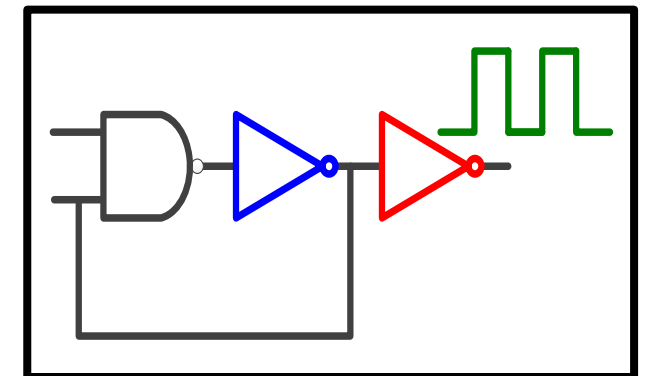


Related Work

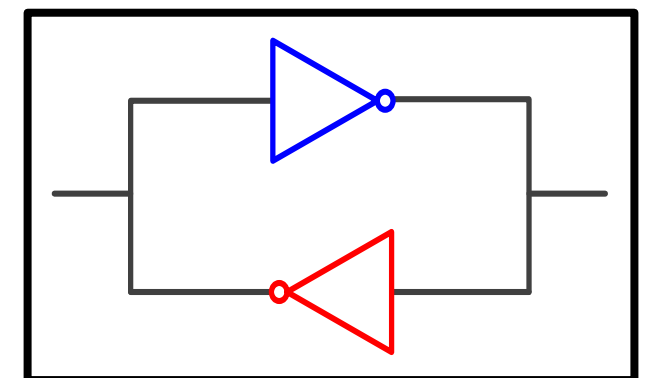
- Arbiter PUF (Lee et al. VLSI'04)
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- Ring Oscillator PUF (Suh et al. DAC'07)
 - Delay loops feeding oscillations into counters
- SRAM PUF (Guajardo et al. CHES'07)
 - Power-on states of 6T SRAM cell



Arbiter PUF



Ring Oscillator PUF

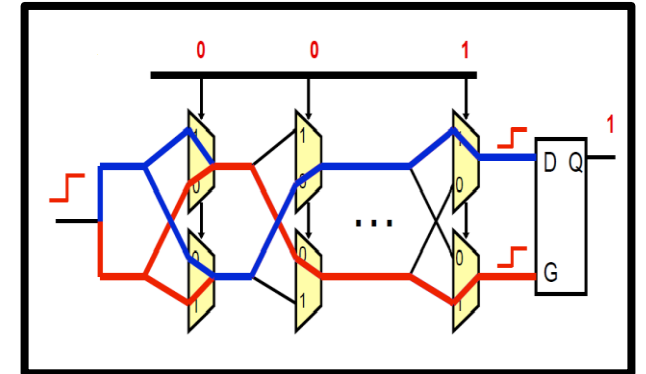


SRAM PUF



Related Work

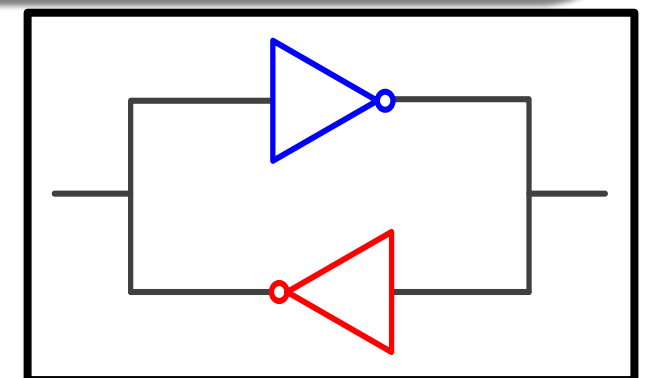
- Arbiter PUF (Lee et al. VLSI'04)
- Signal traversing maze of cascaded switch blocks



Authenticache: No custom hardware

On-chip error correction logic in processor caches

- SRAM PUF (Guajardo et al. CHES'07)
- Power-on states of 6T SRAM cell



SRAM PUF



Cache Errors as Silicon Fingerprints



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- Caches optimized for density



Cache Errors as Silicon Fingerprints

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- Sensitive to process variation



Cache Errors as Silicon Fingerprints

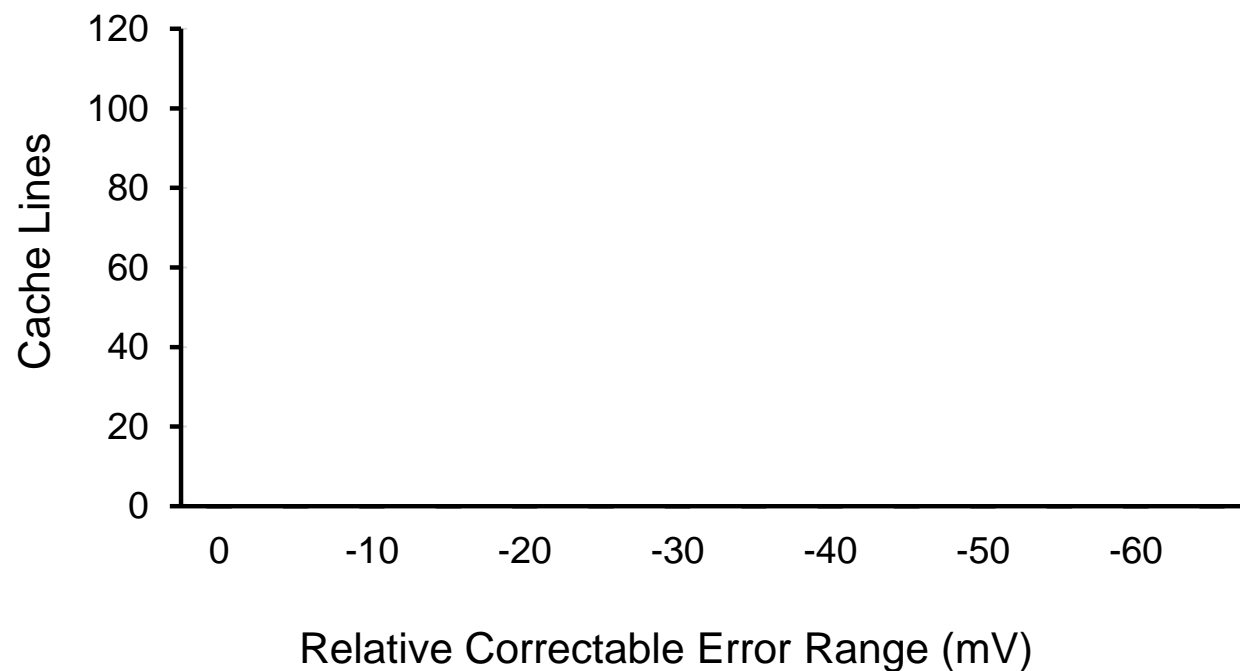
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- Itanium processor 8 L2 caches





Cache Errors as Silicon Fingerprints

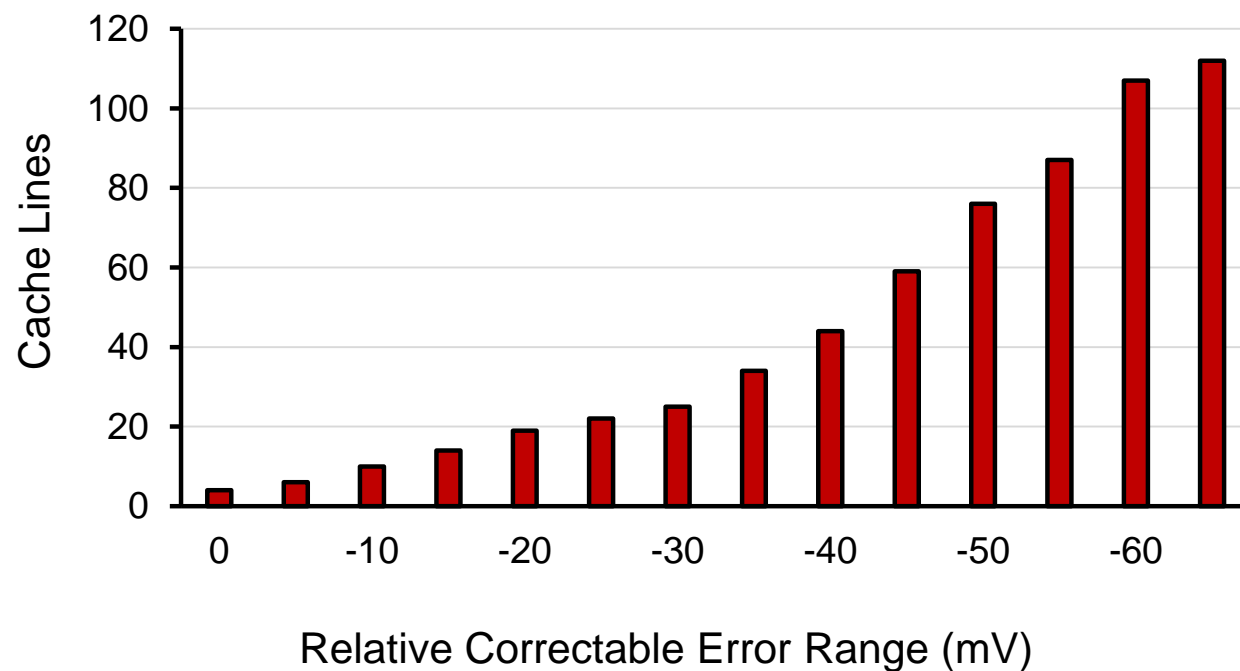
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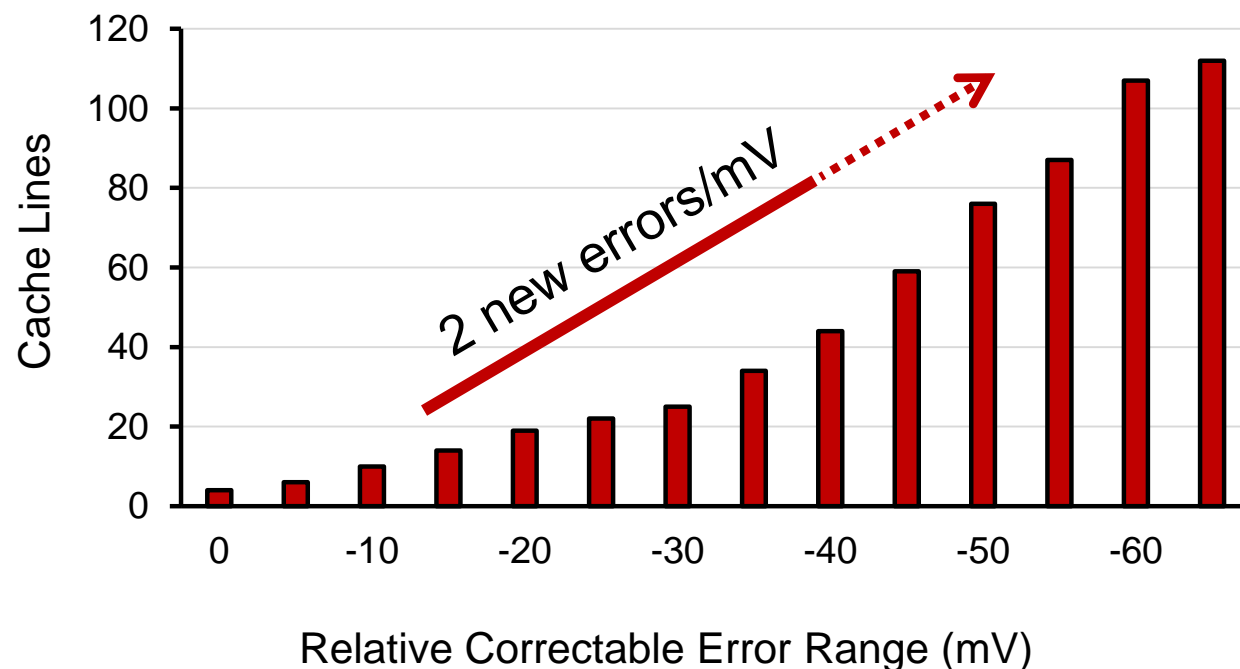
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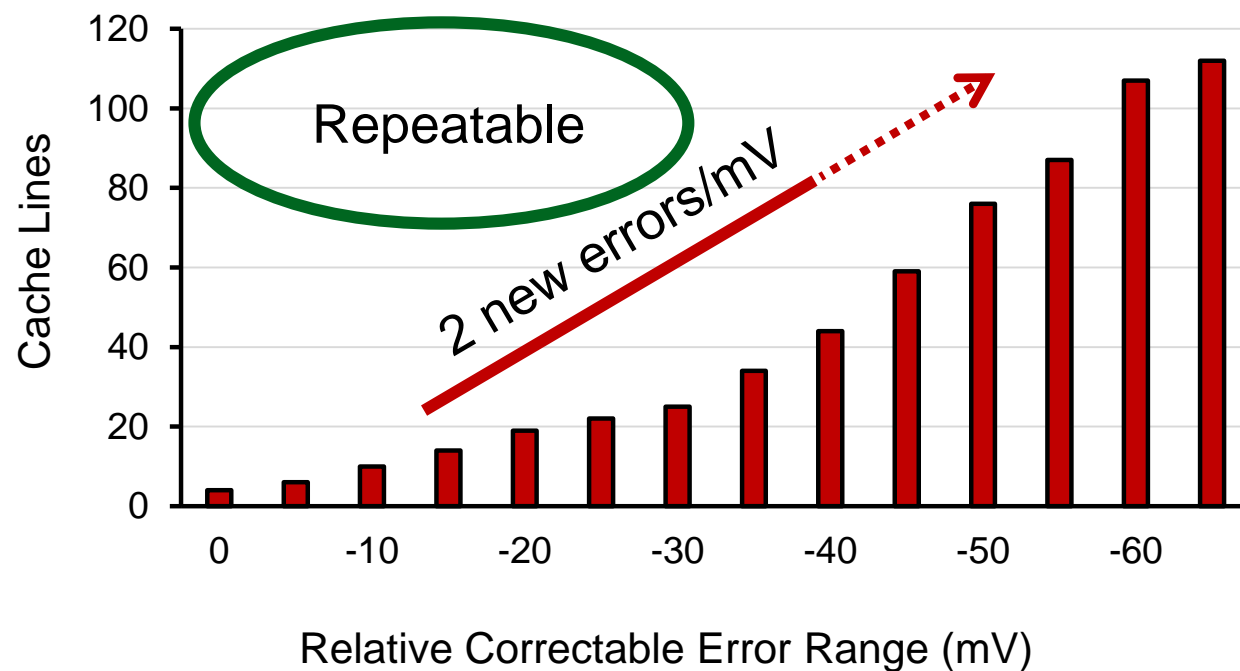
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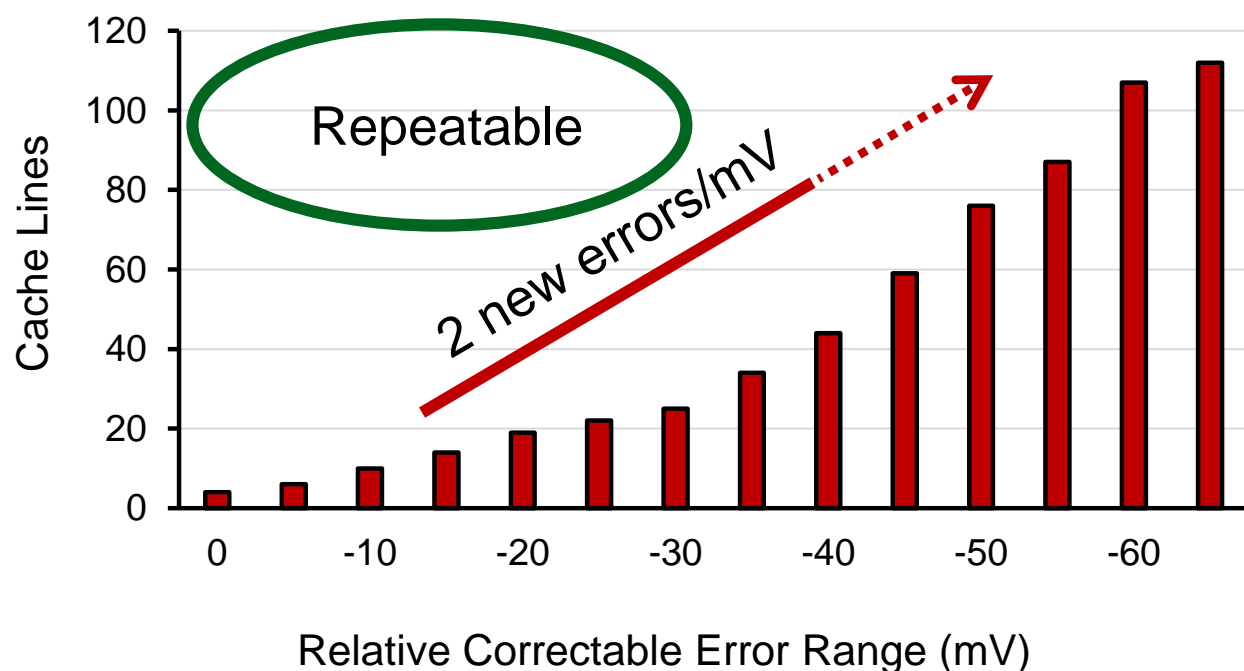
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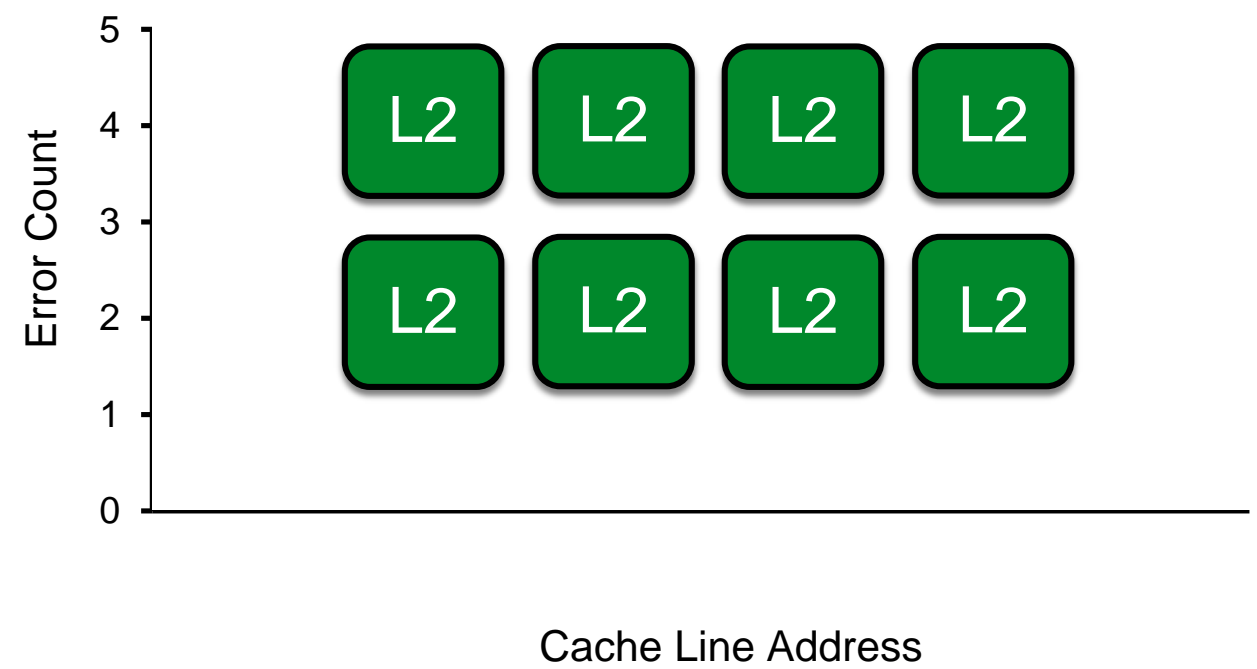
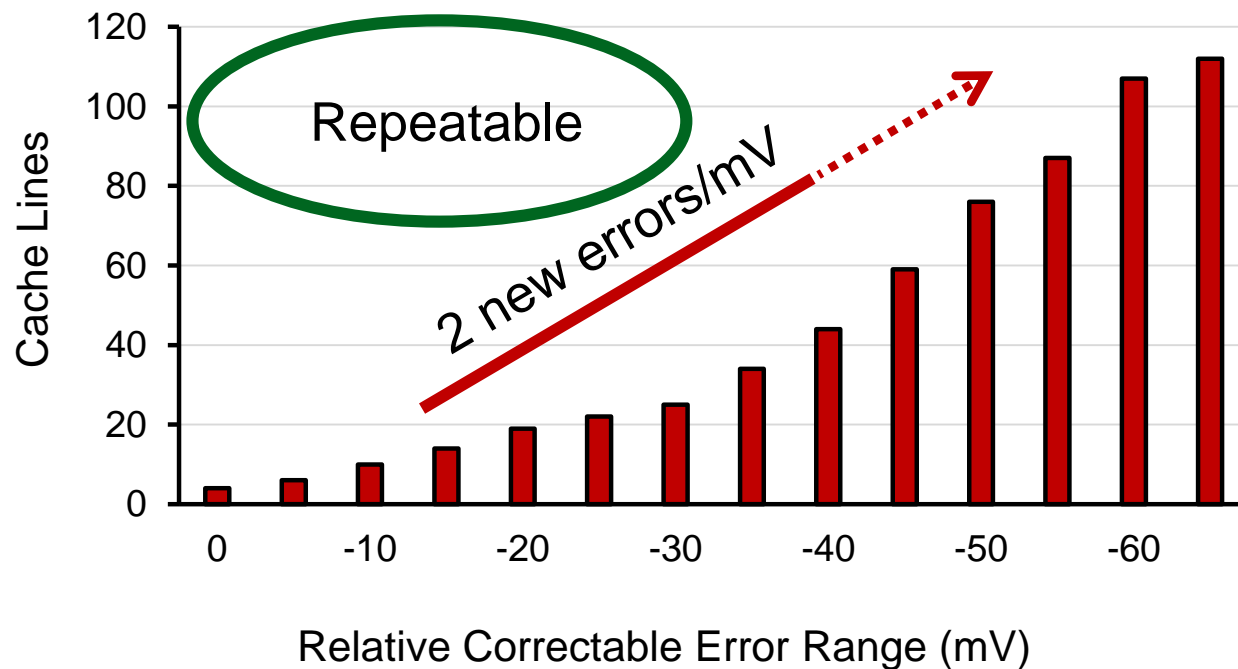
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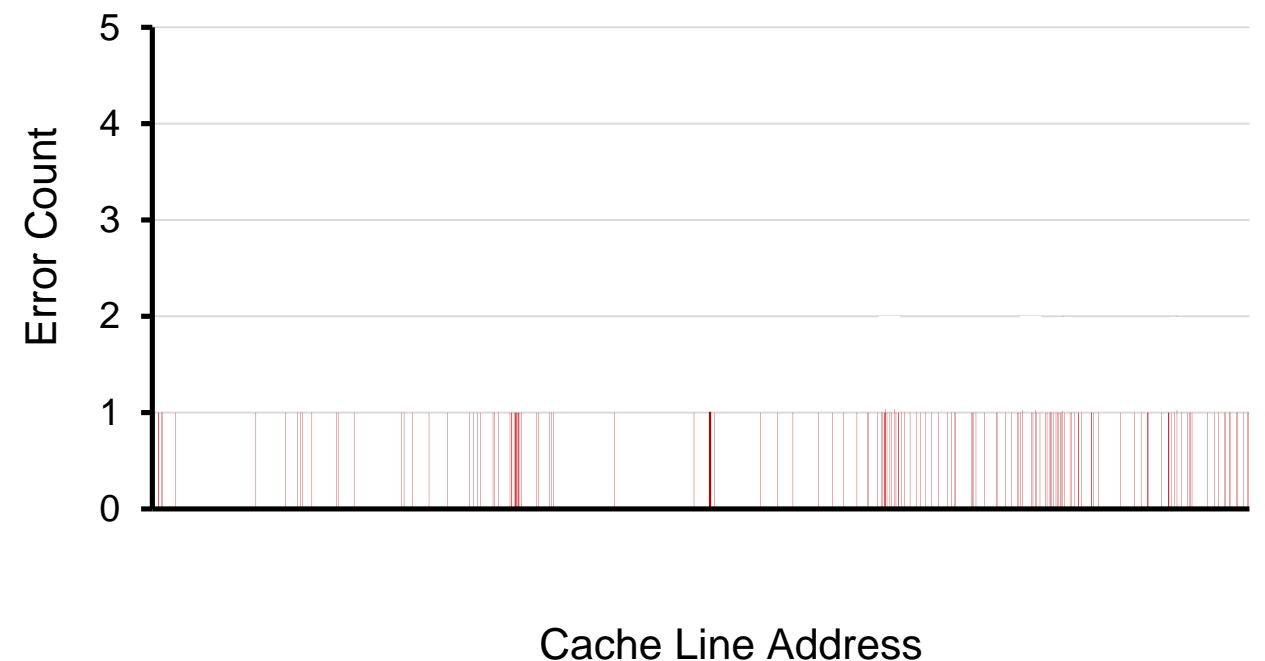
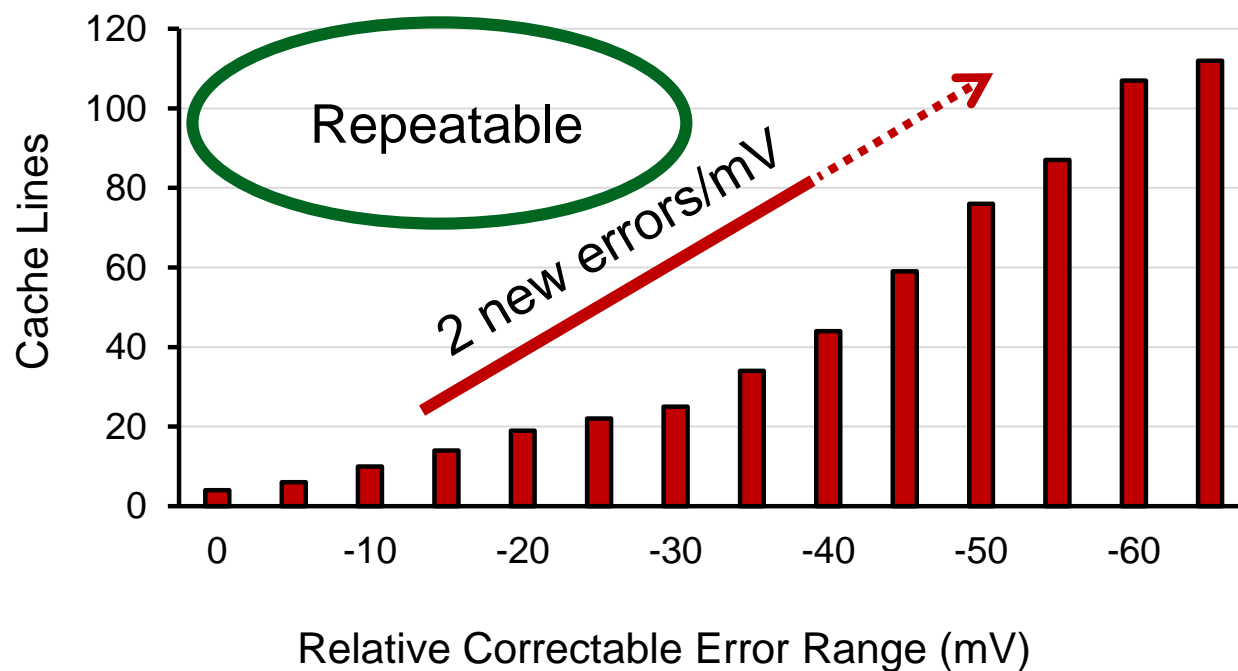
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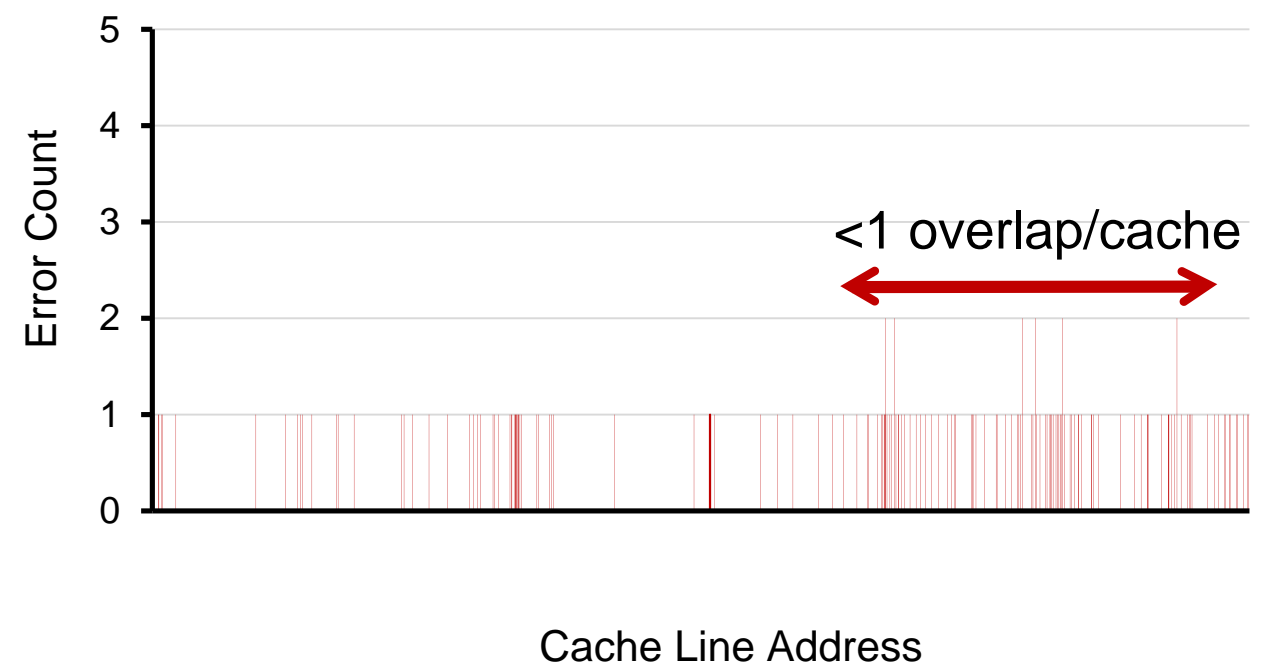
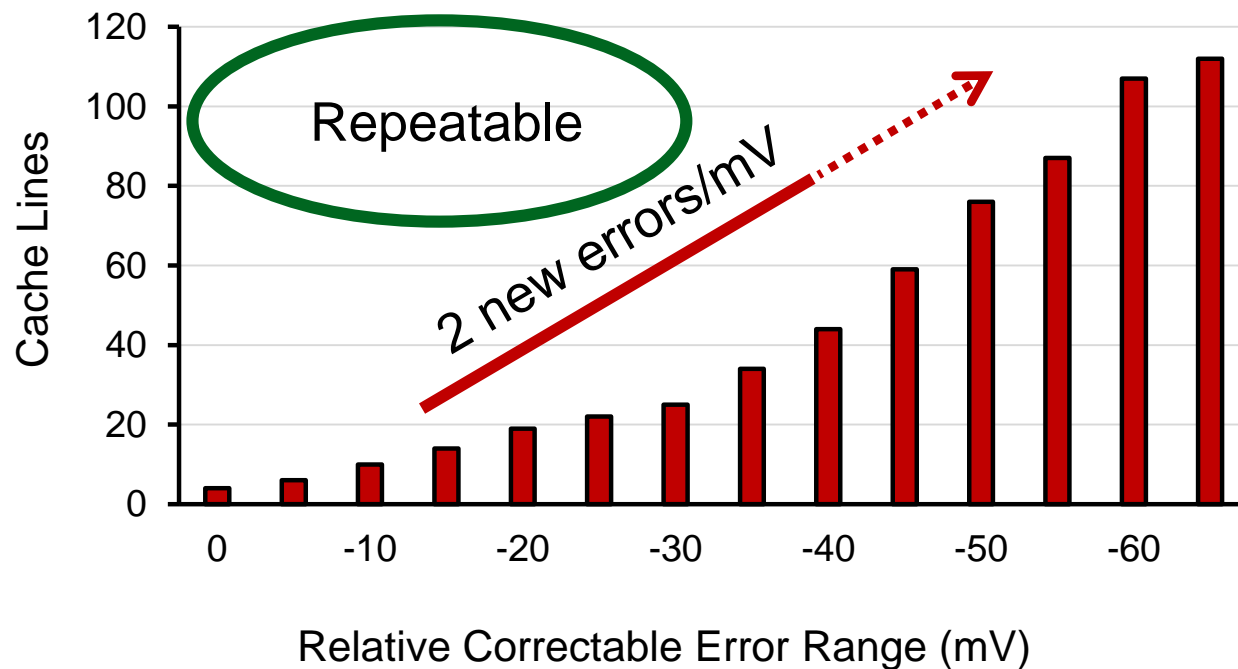
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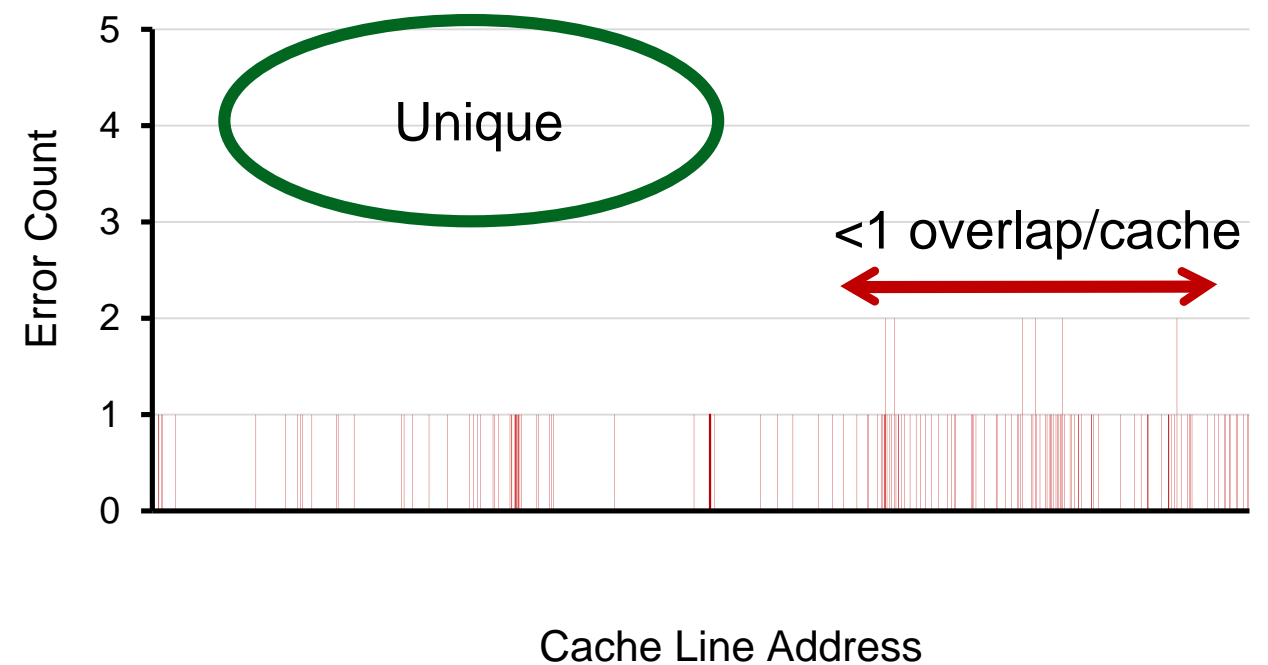
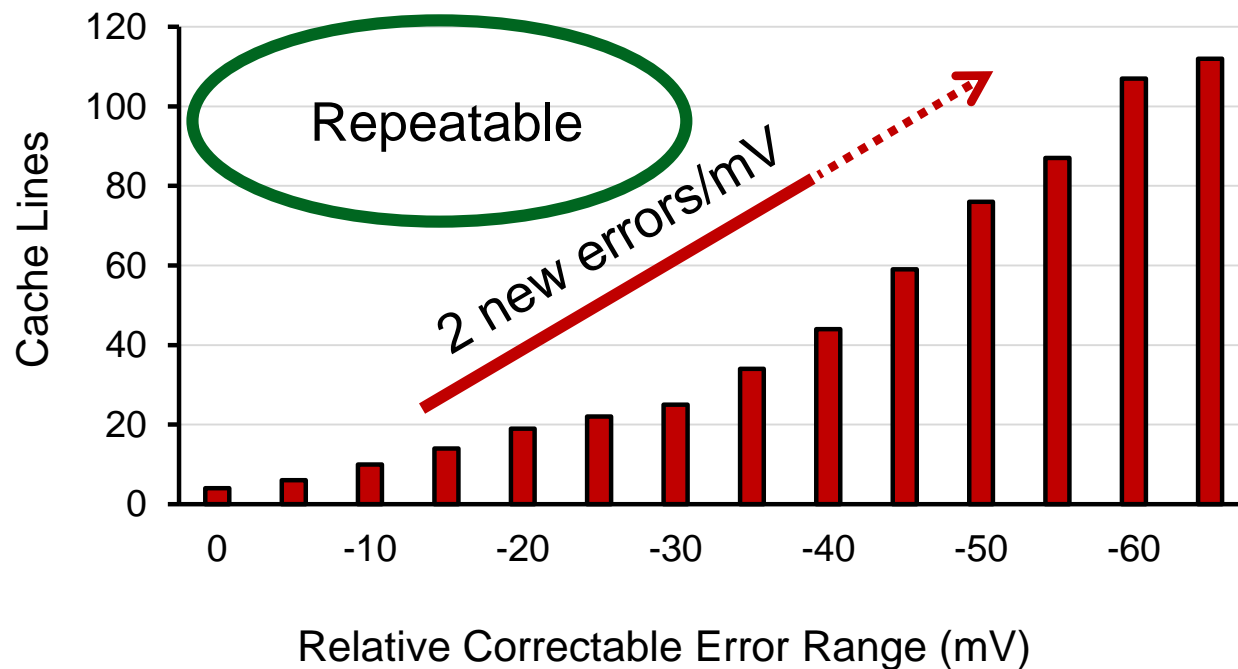


Cache Errors as Silicon Fingerprints

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Intel 9560 Processor



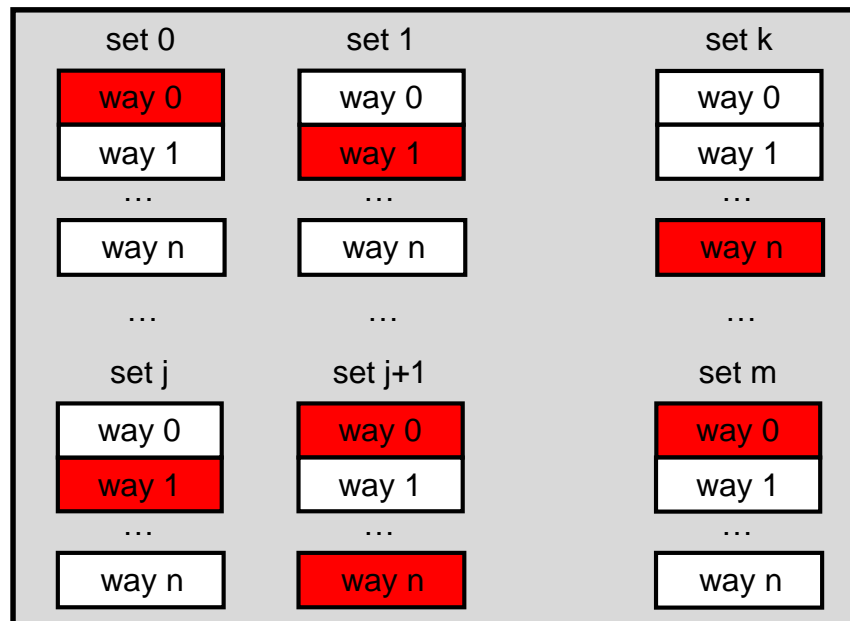


The Authenticache System



The Authenticache System

Cache Layout

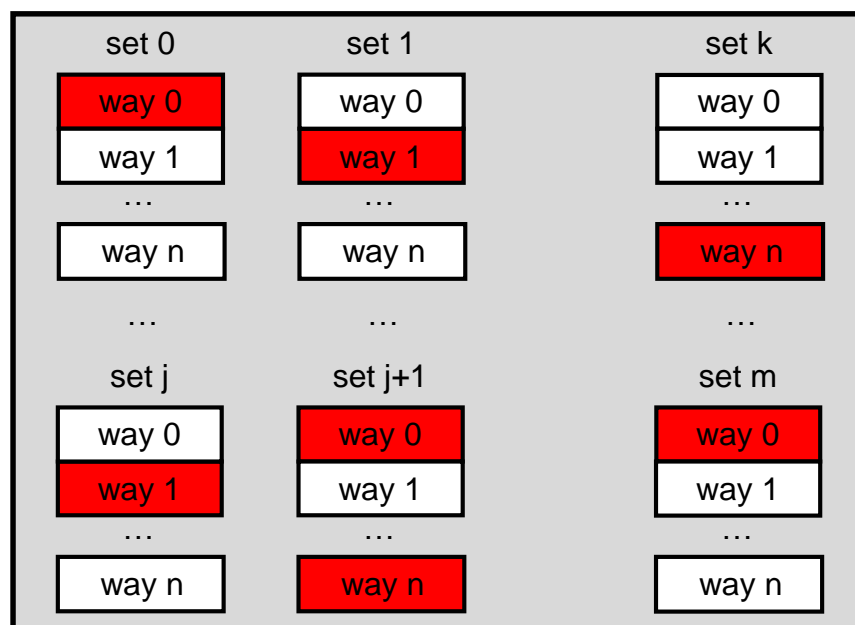


- Exploit process variation in LLC for randomness

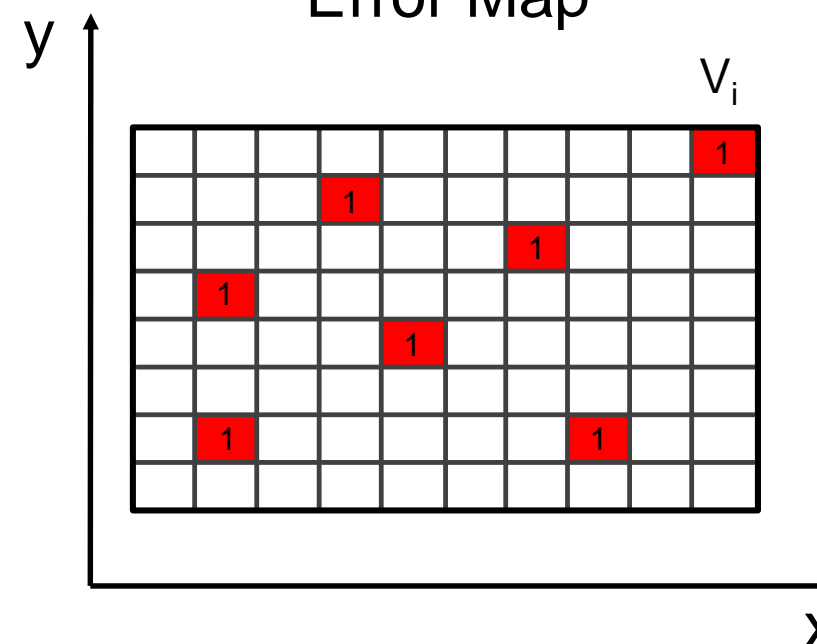


The Authenticache System

Cache Layout



Error Map



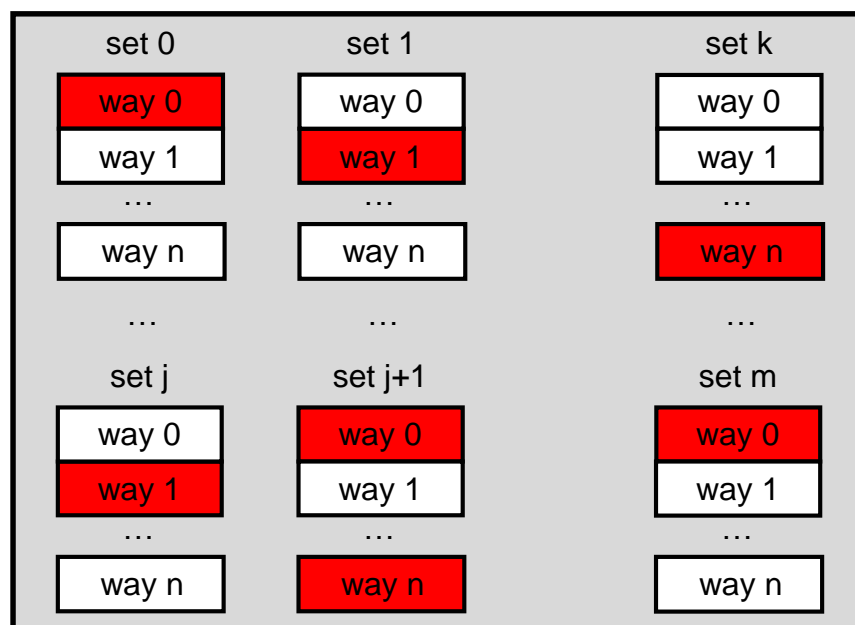
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- Construct cache maps as a function of voltage and correctable errors

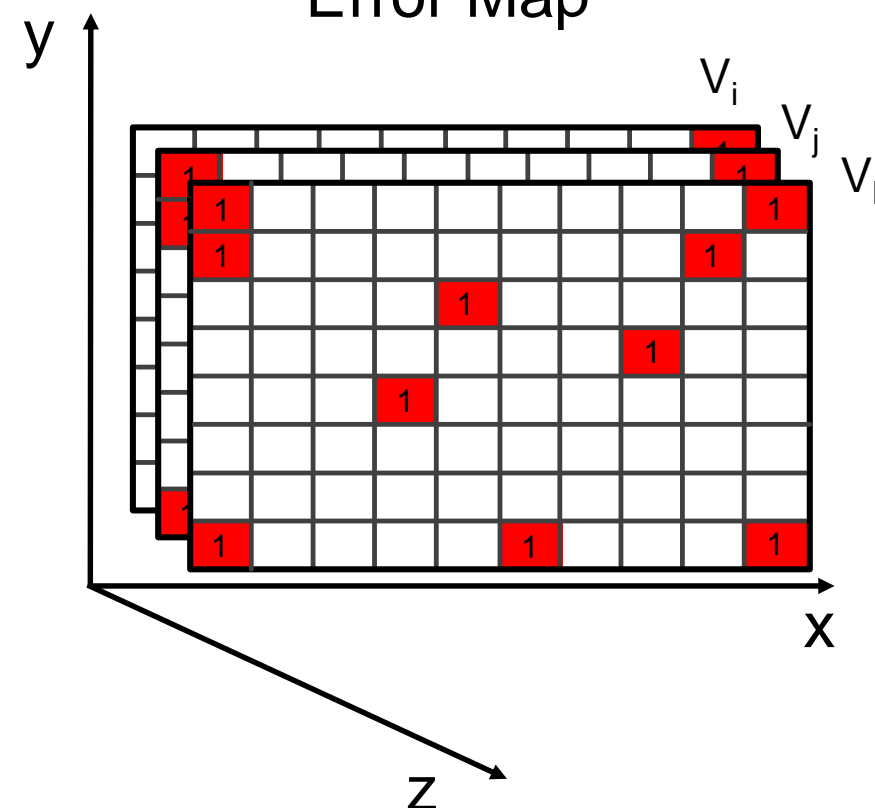


The Authenticache System

Cache Layout



Error Map



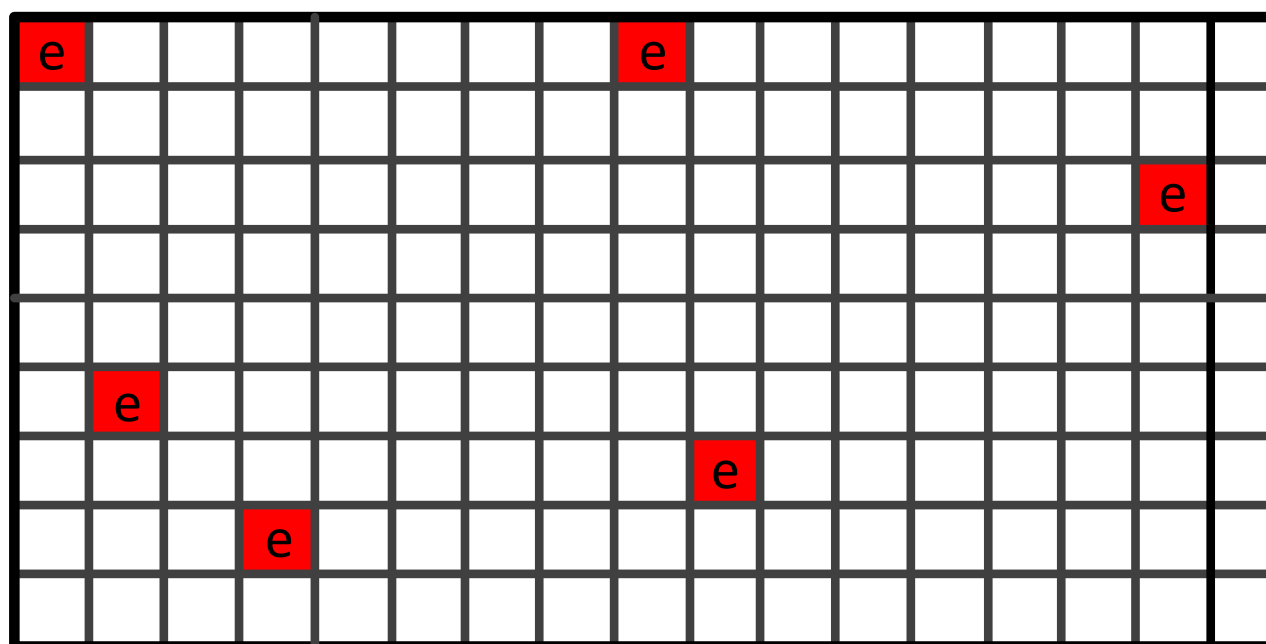
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Challenge and Response

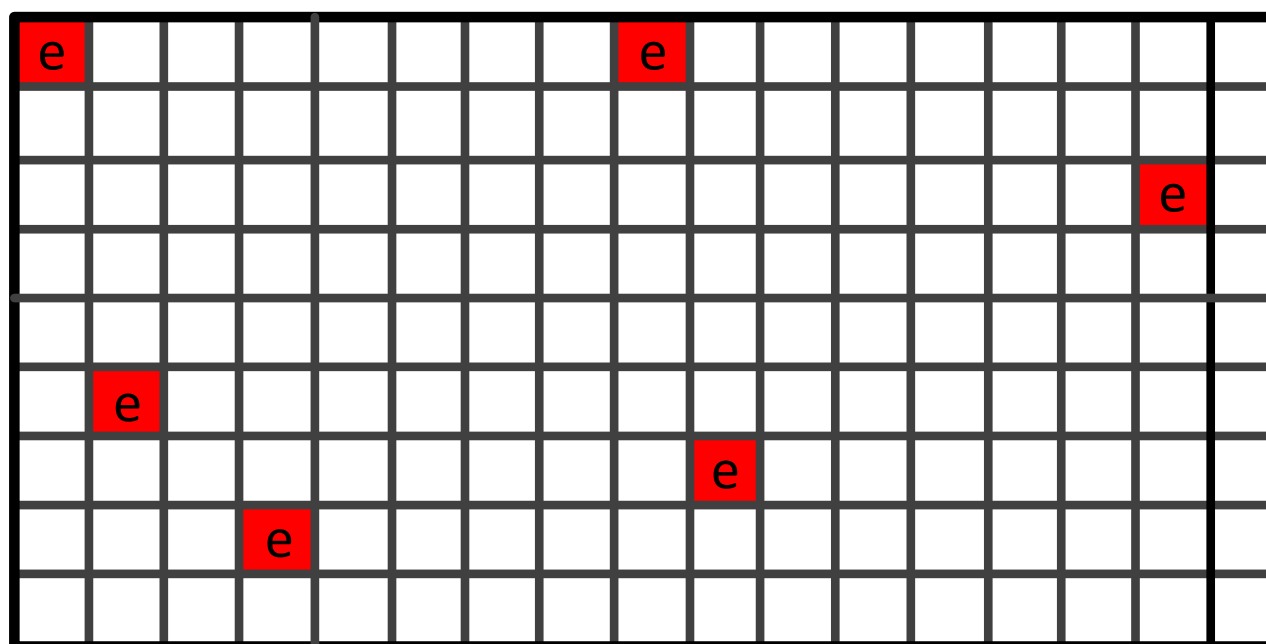
Error Map





Challenge and Response

Error Map

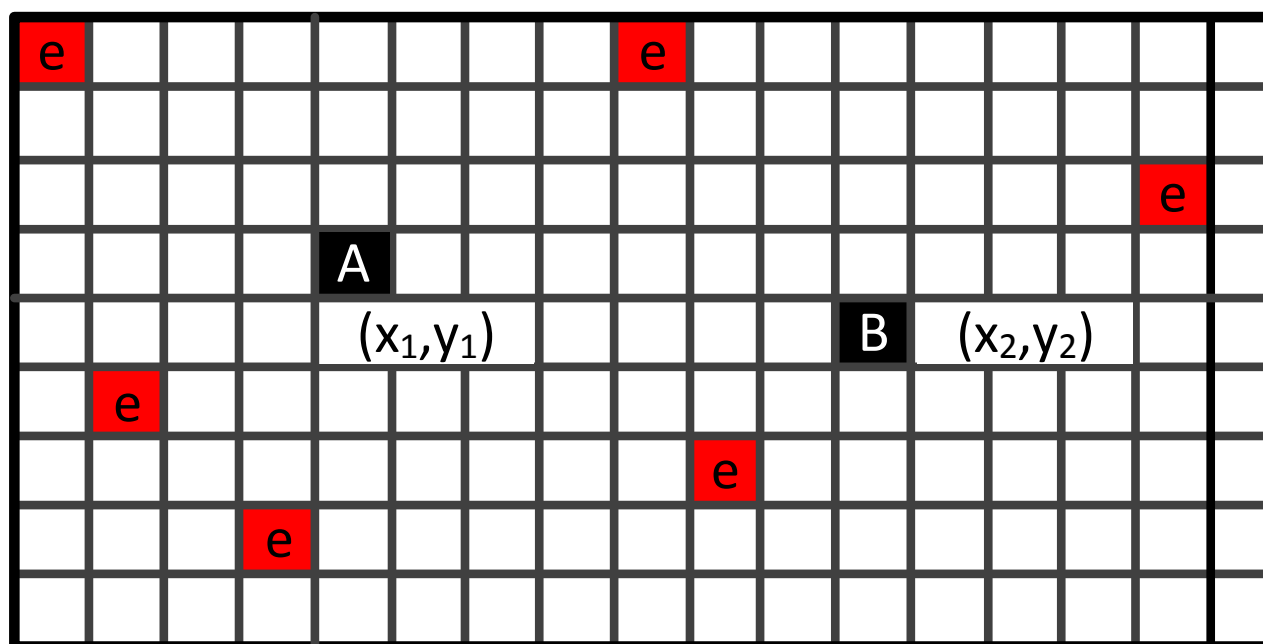


$$\text{Challenge} = (\underbrace{x_1, y_1, V_1}_A), (\underbrace{x_2, y_2, V_2}_B)$$



Challenge and Response

Error Map

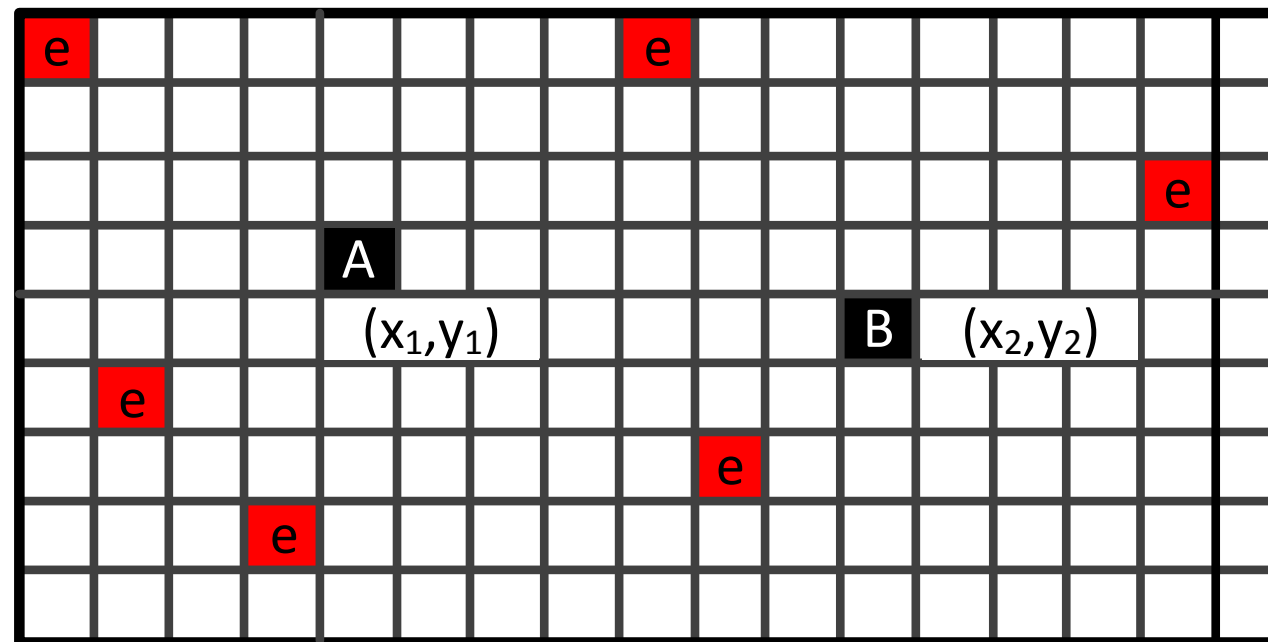


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Challenge and Response

Error Map



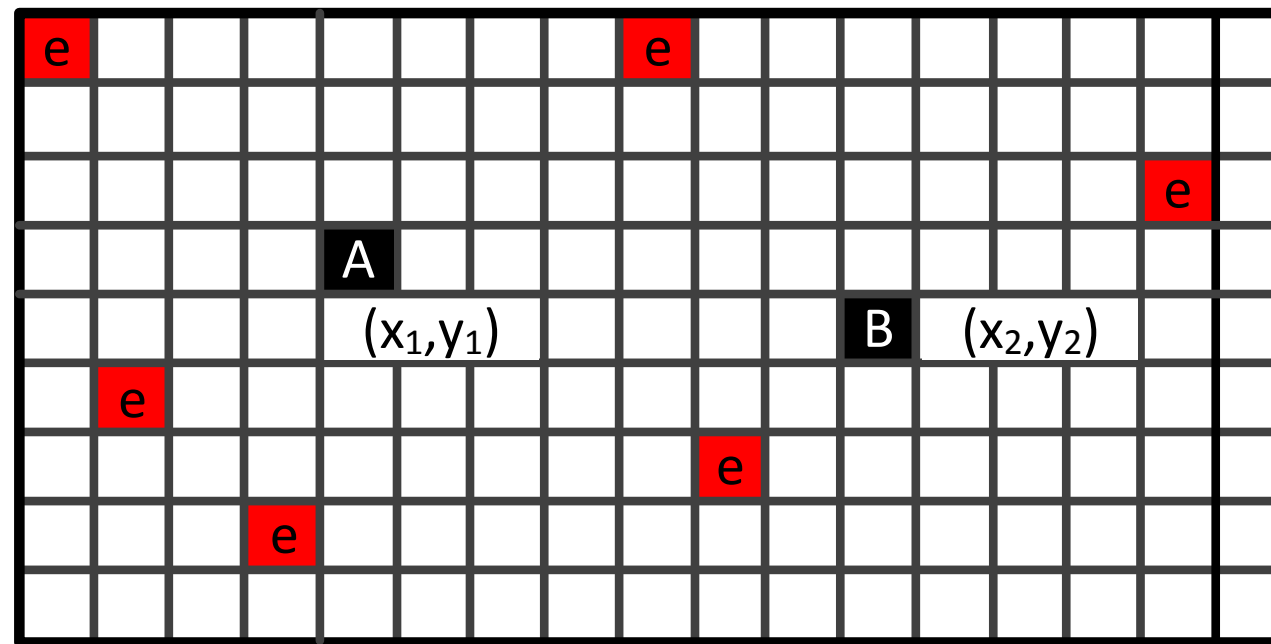
$$V_1 = V_2$$

$$\text{Challenge} = \underbrace{(x_1, y_1, V_1)}_A, \underbrace{(x_2, y_2, V_2)}_B$$



Challenge and Response

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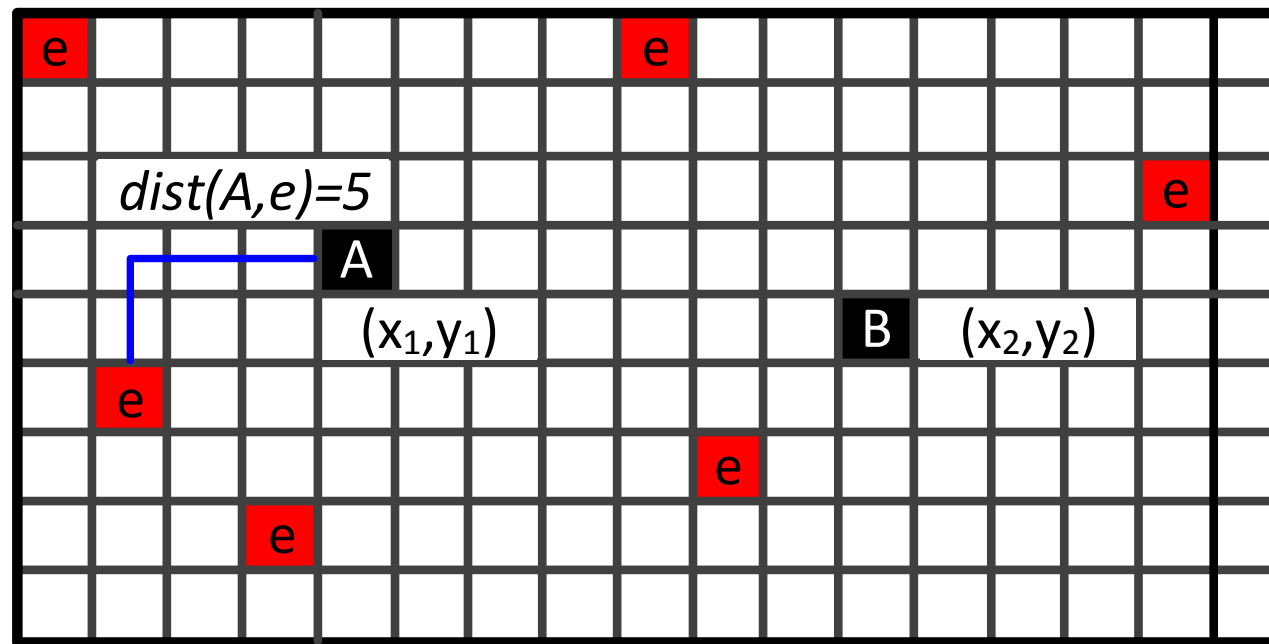
$$\text{Response} = \begin{cases} 0, & \text{dist}(A, e_a) < \text{dist}(B, e_b) \\ 1, & \text{dist}(A, e_a) \geq \text{dist}(B, e_b) \end{cases}$$

Manhattan Distance



Challenge and Response

Error Map



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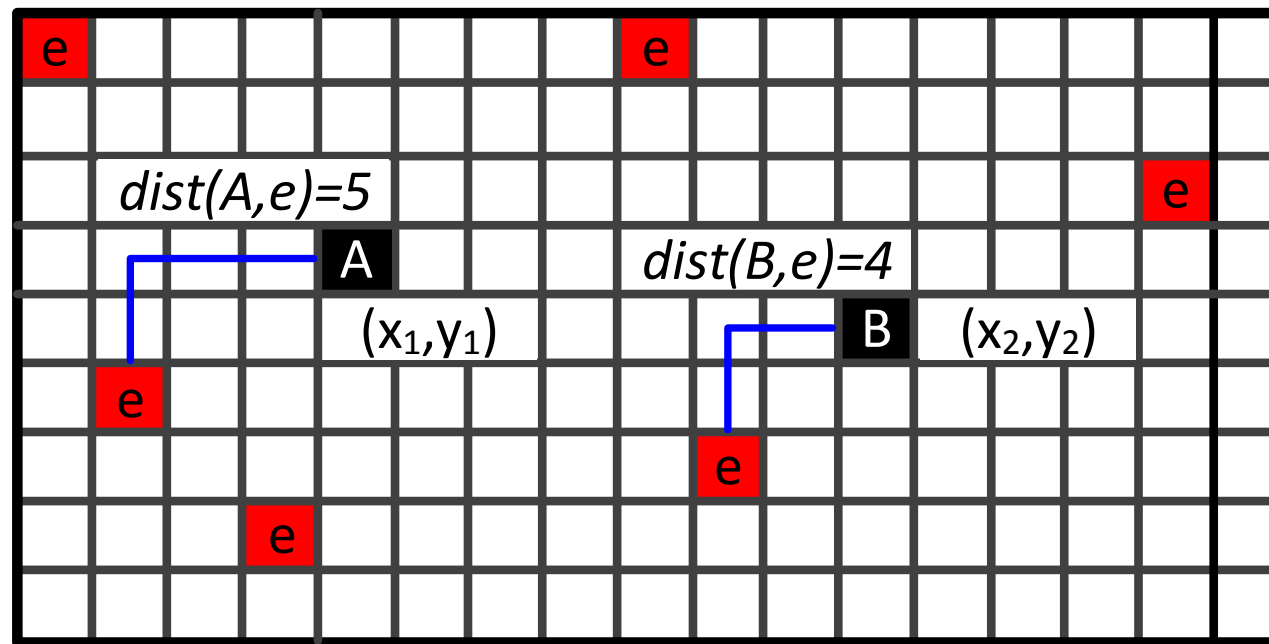
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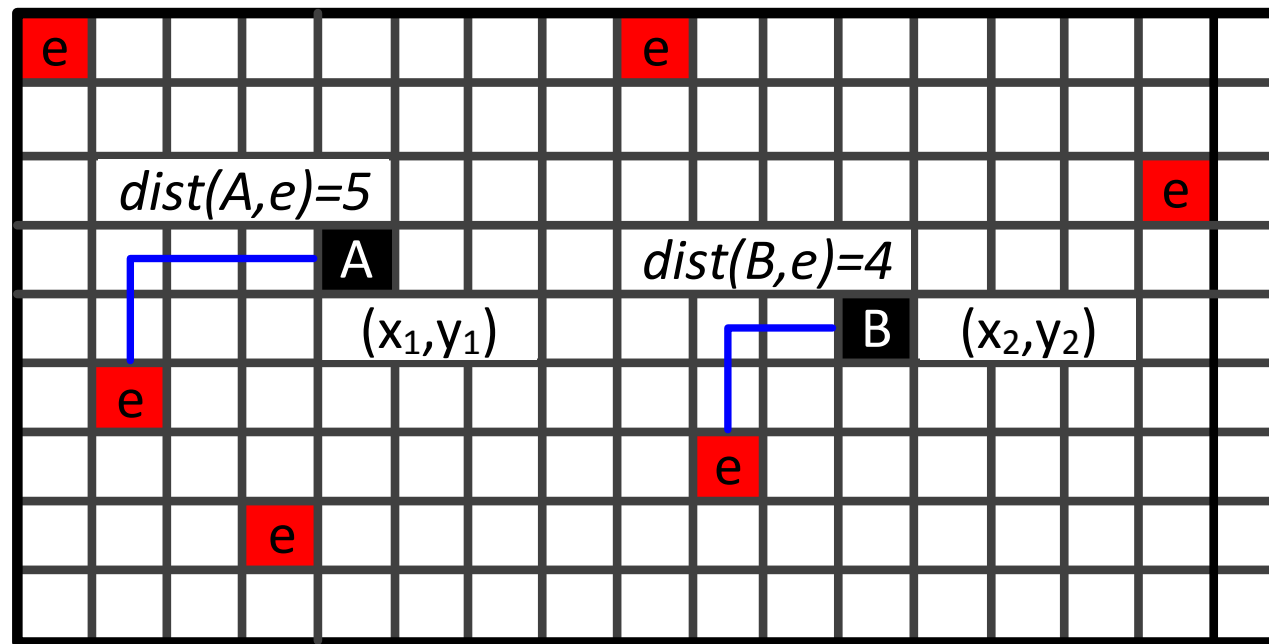
Manhattan Distance



Challenge and Response

5 > 4

Error Map



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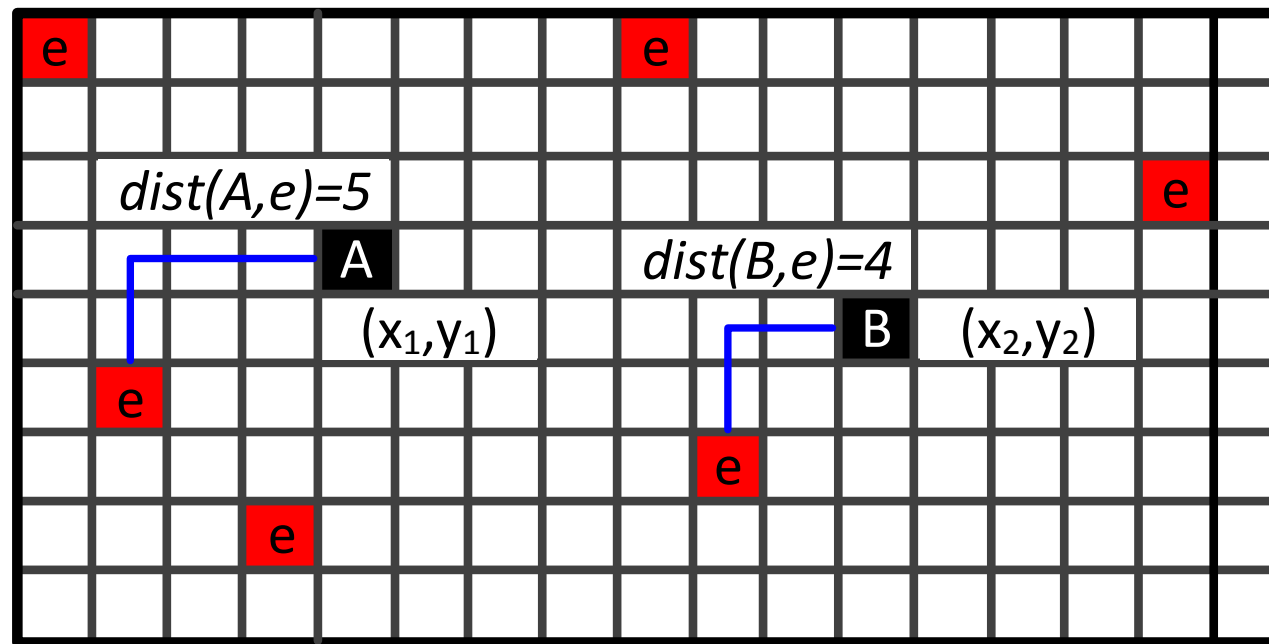
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Challenge and Response

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$V_1 = V_2$

1

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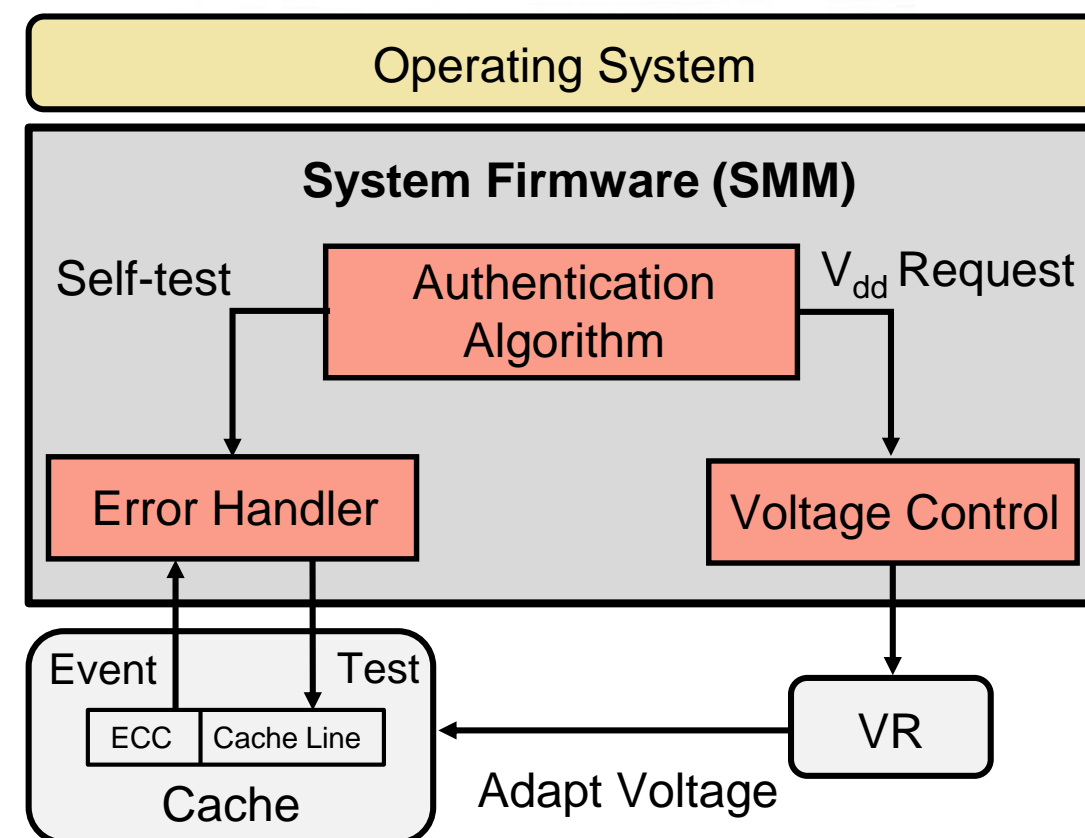
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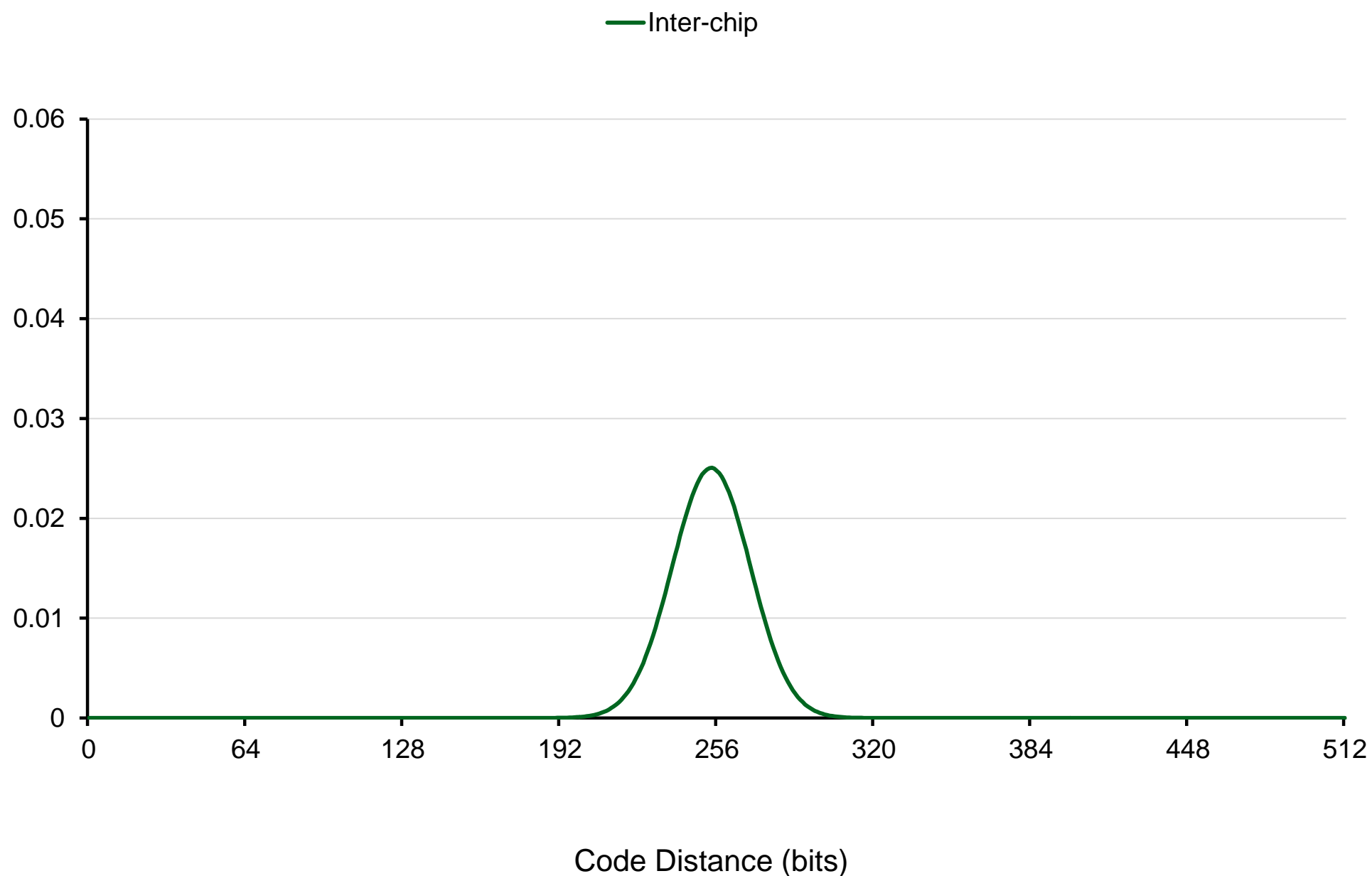
Experimental Framework

- System:
 - BL860c-i4 Integrity Server from HP
 - 2x 9560 Itanium II CPUs
- Prototype in System Firmware
 - Thermal experiments through power virus
- Monte Carlo simulations
 - Different cache sizes
 - Different error maps and noise profiles





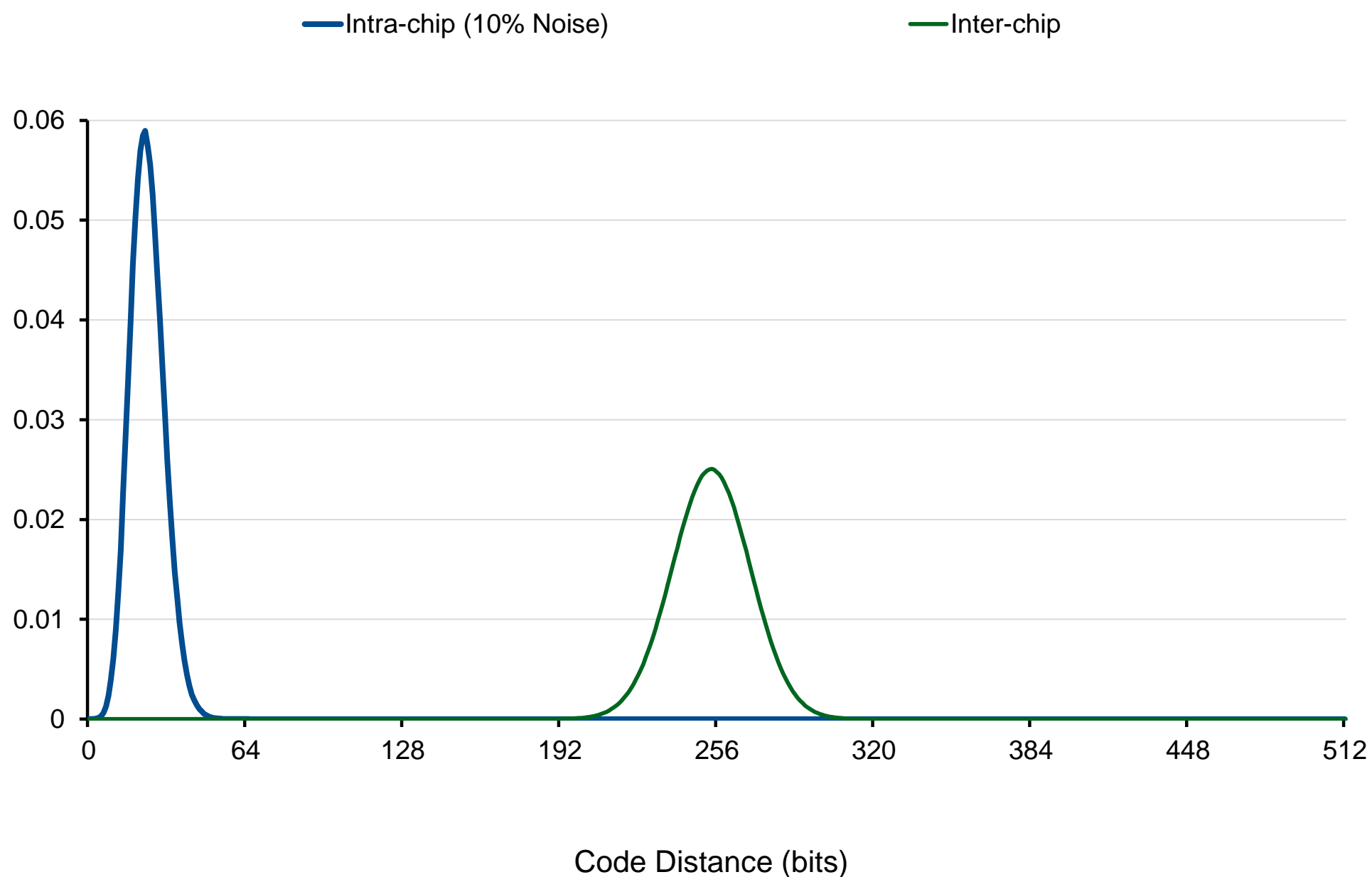
Identification and Noise



Identification in presence of environmental and measurement noise



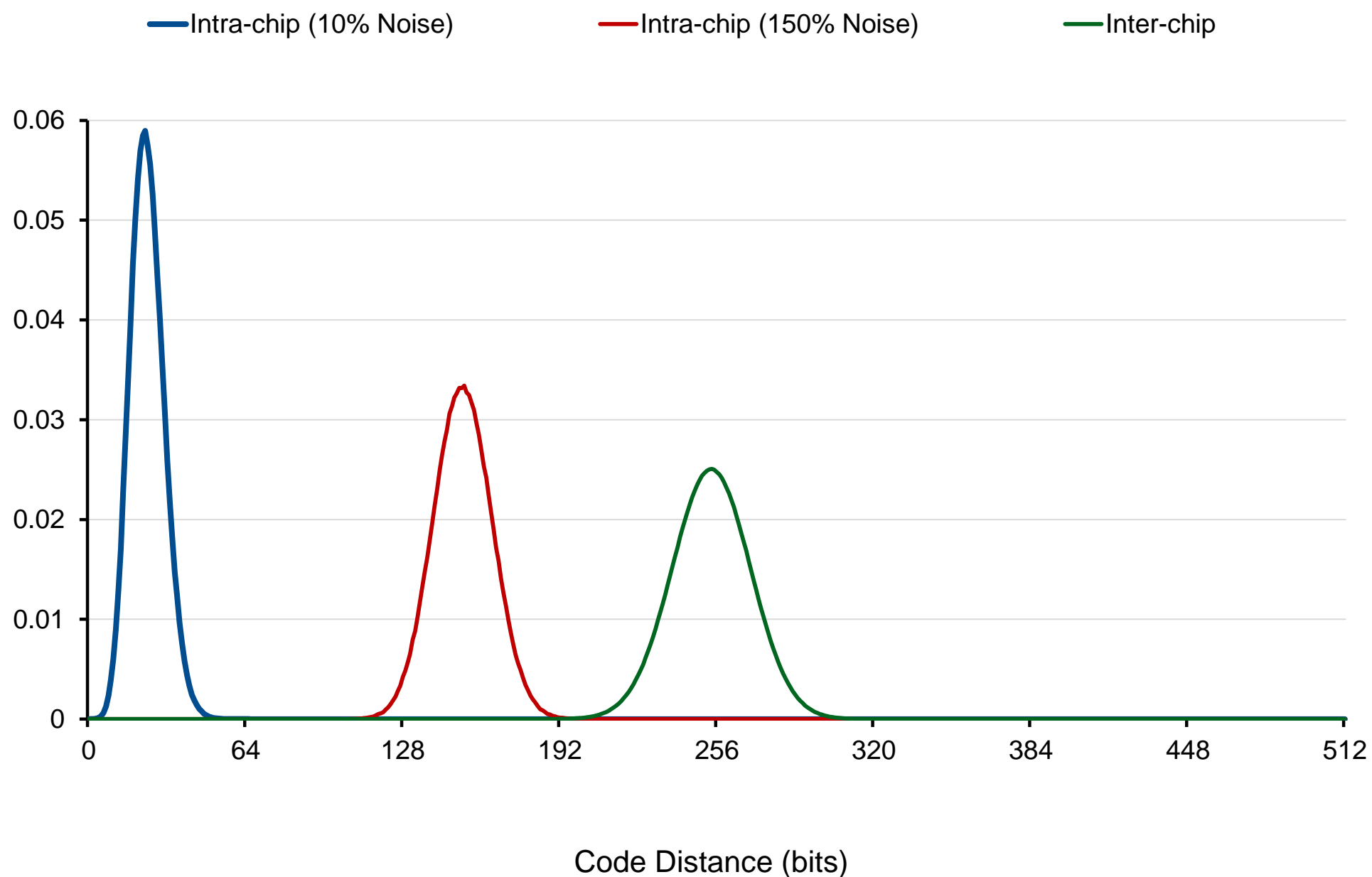
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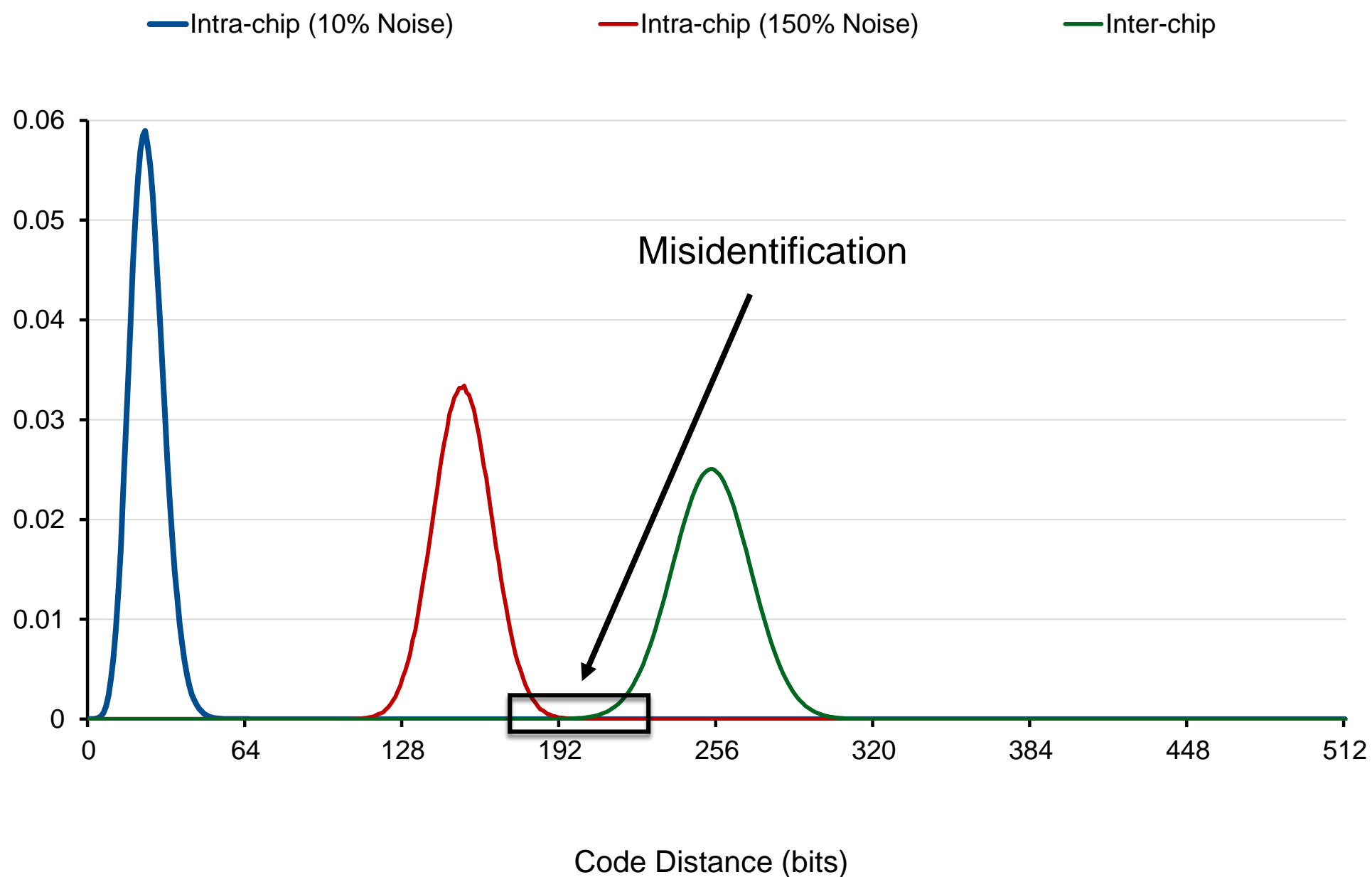
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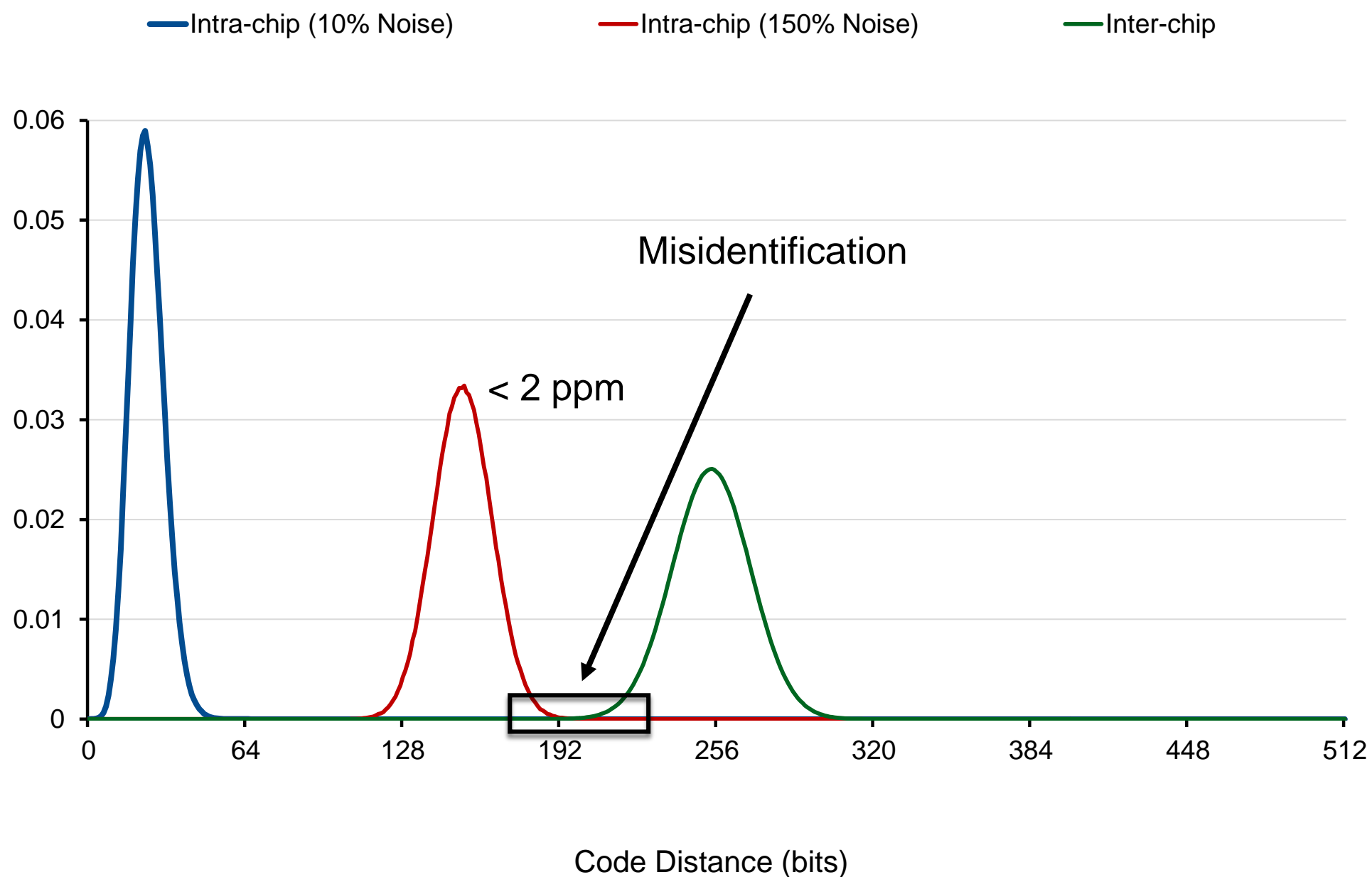
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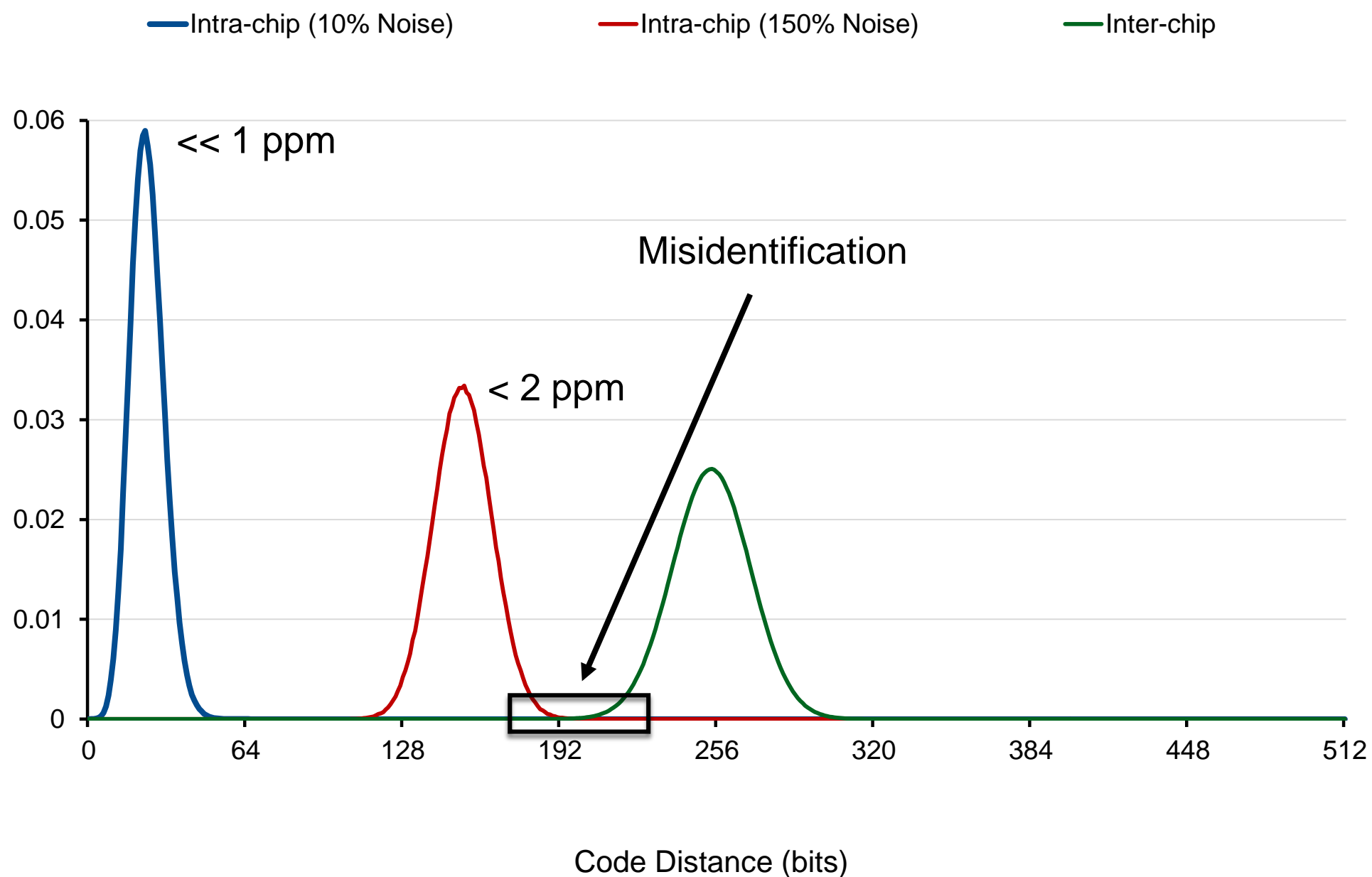
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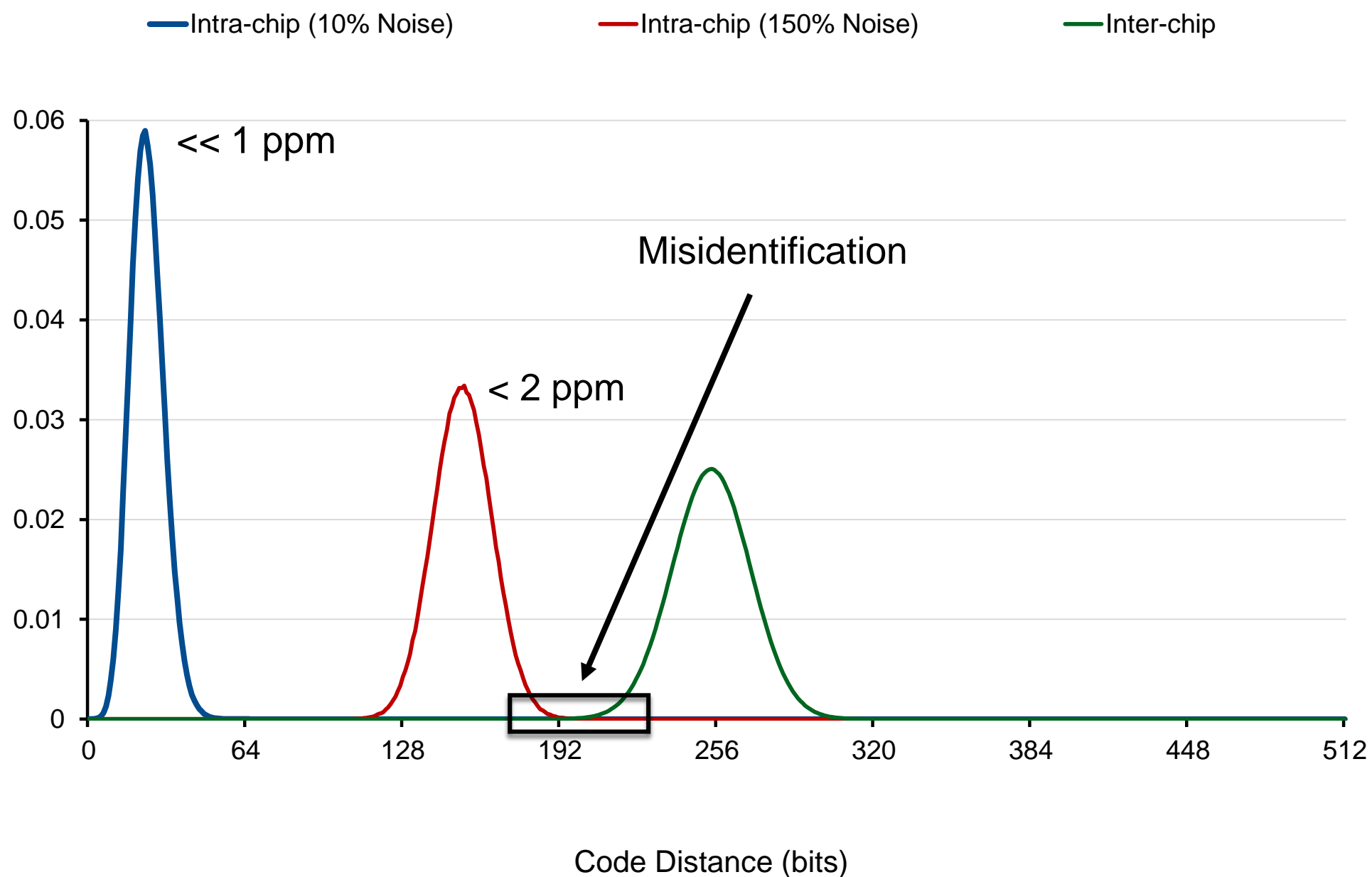
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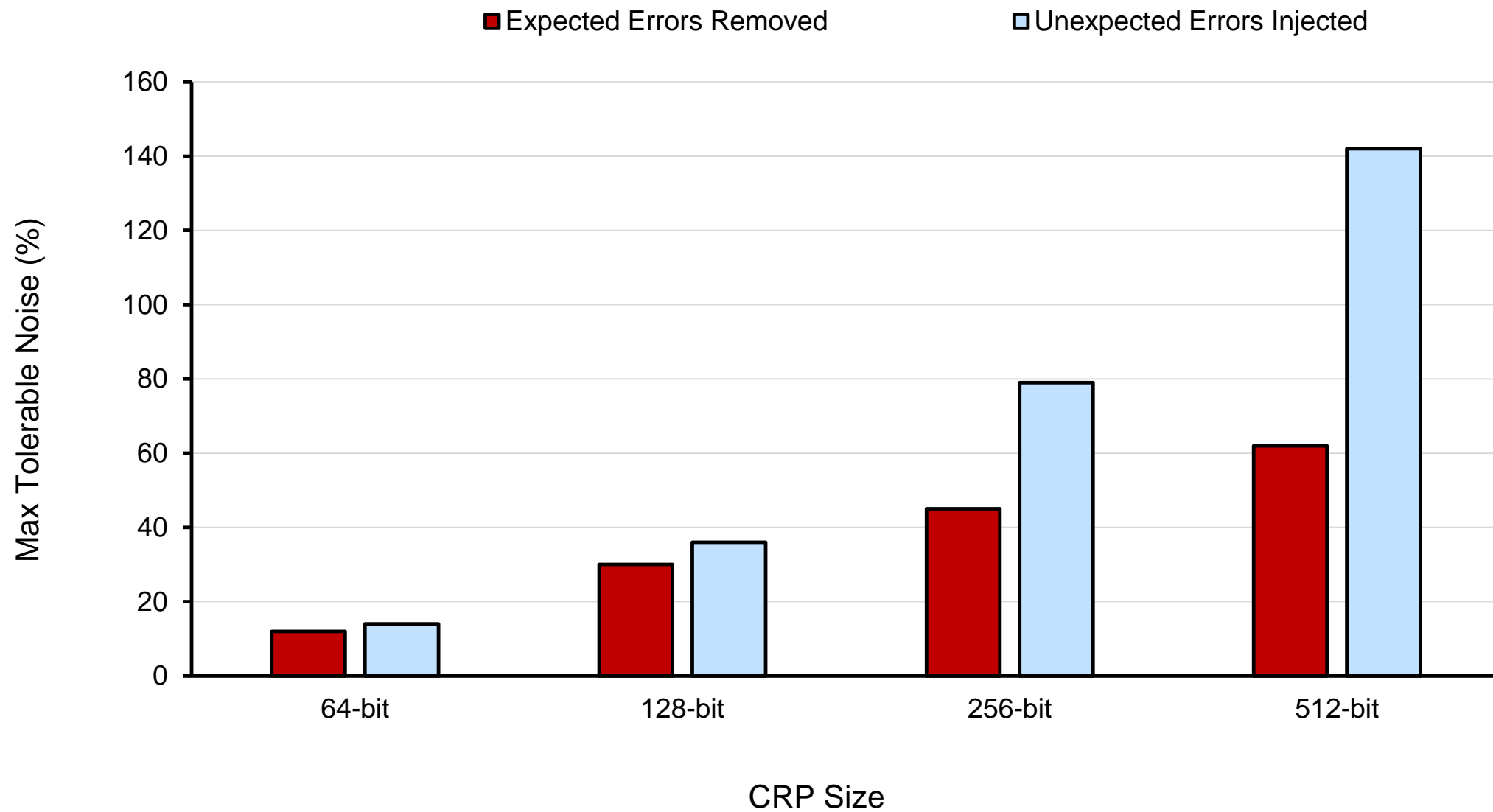
Identification and Noise



Observe 6% intra-chip variation after +25° C

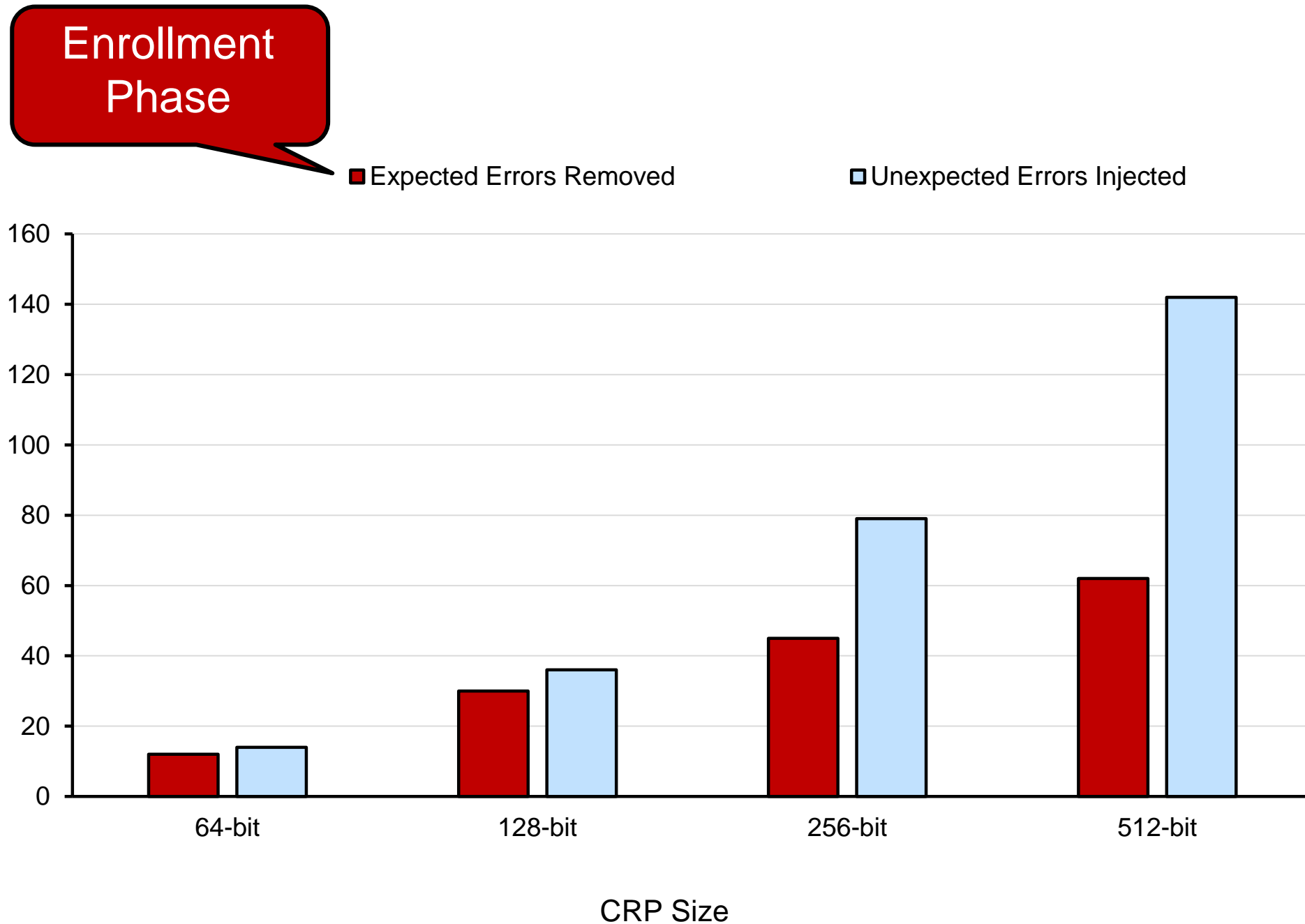


Resiliency to Noise



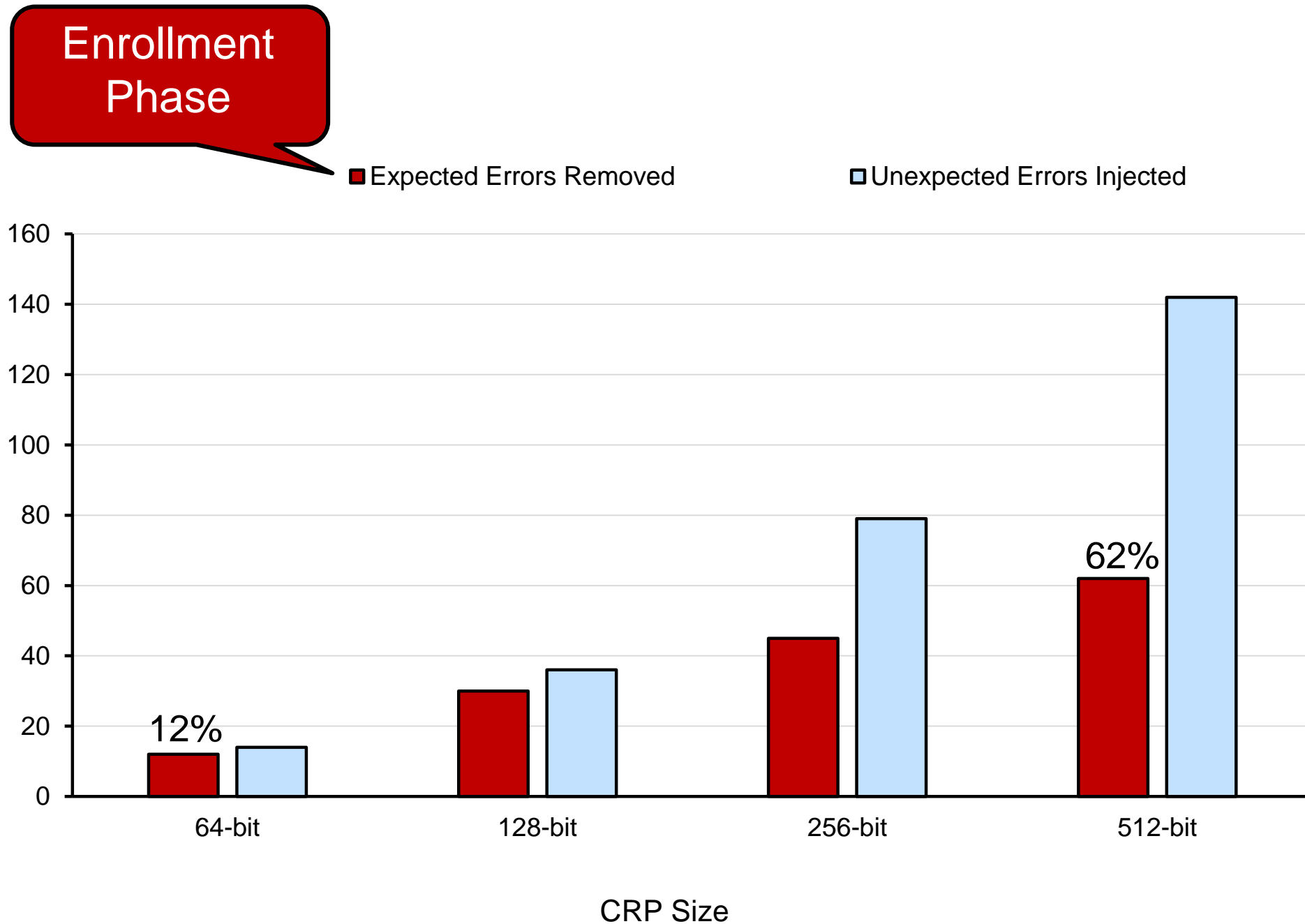


Resiliency to Noise



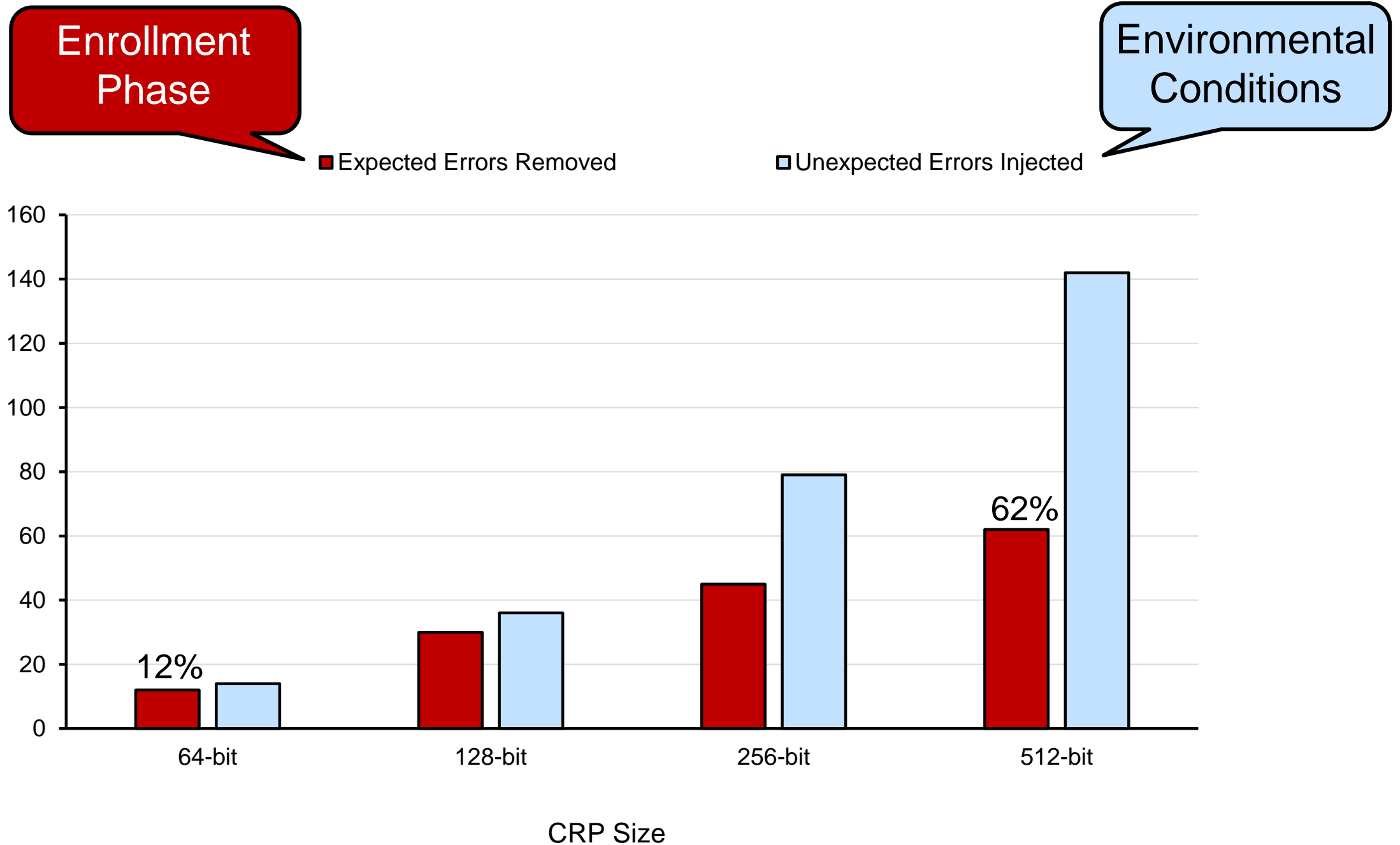


Resiliency to Noise



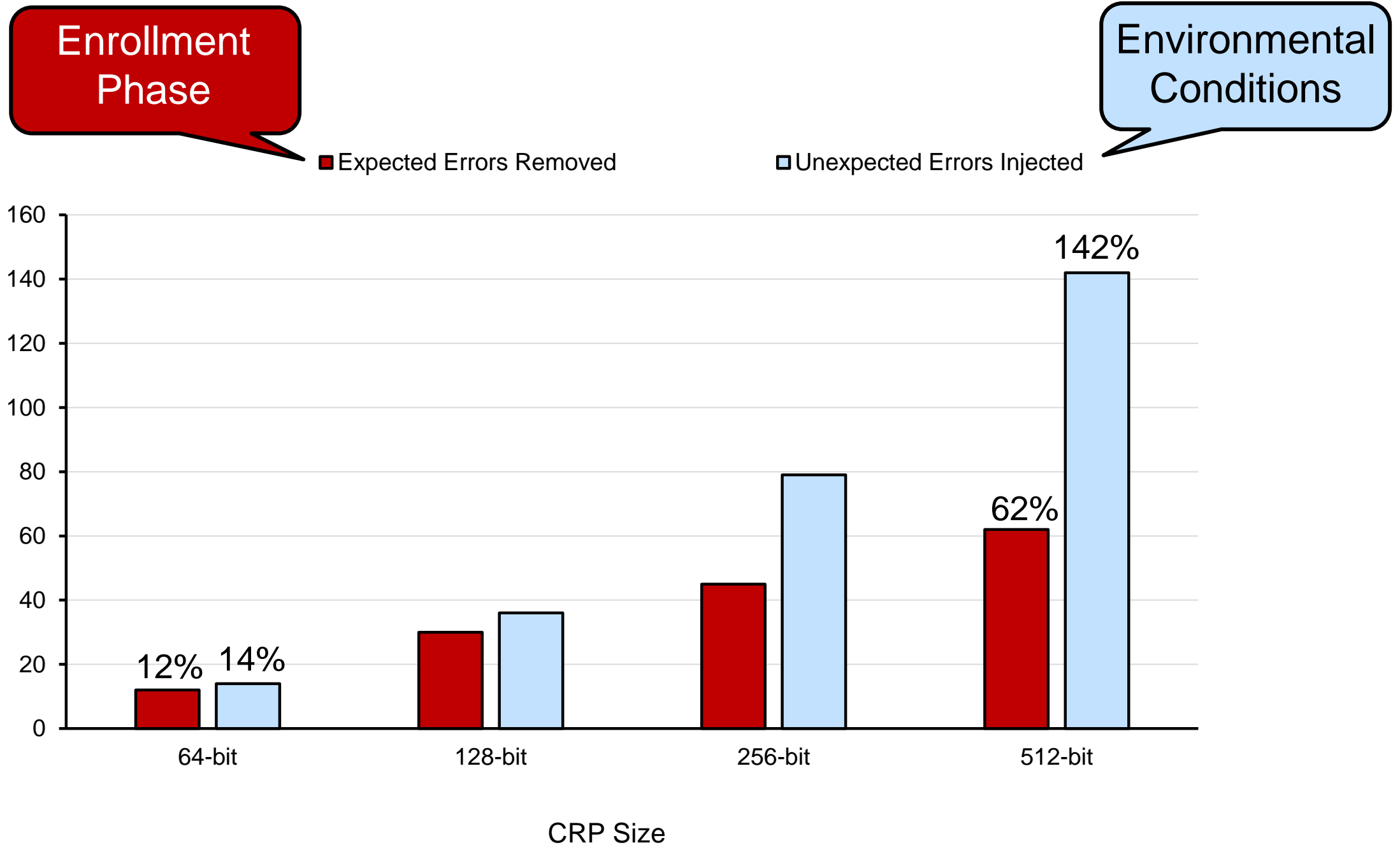


Resiliency to Noise





Resiliency to Noise





Repeatability and Performance



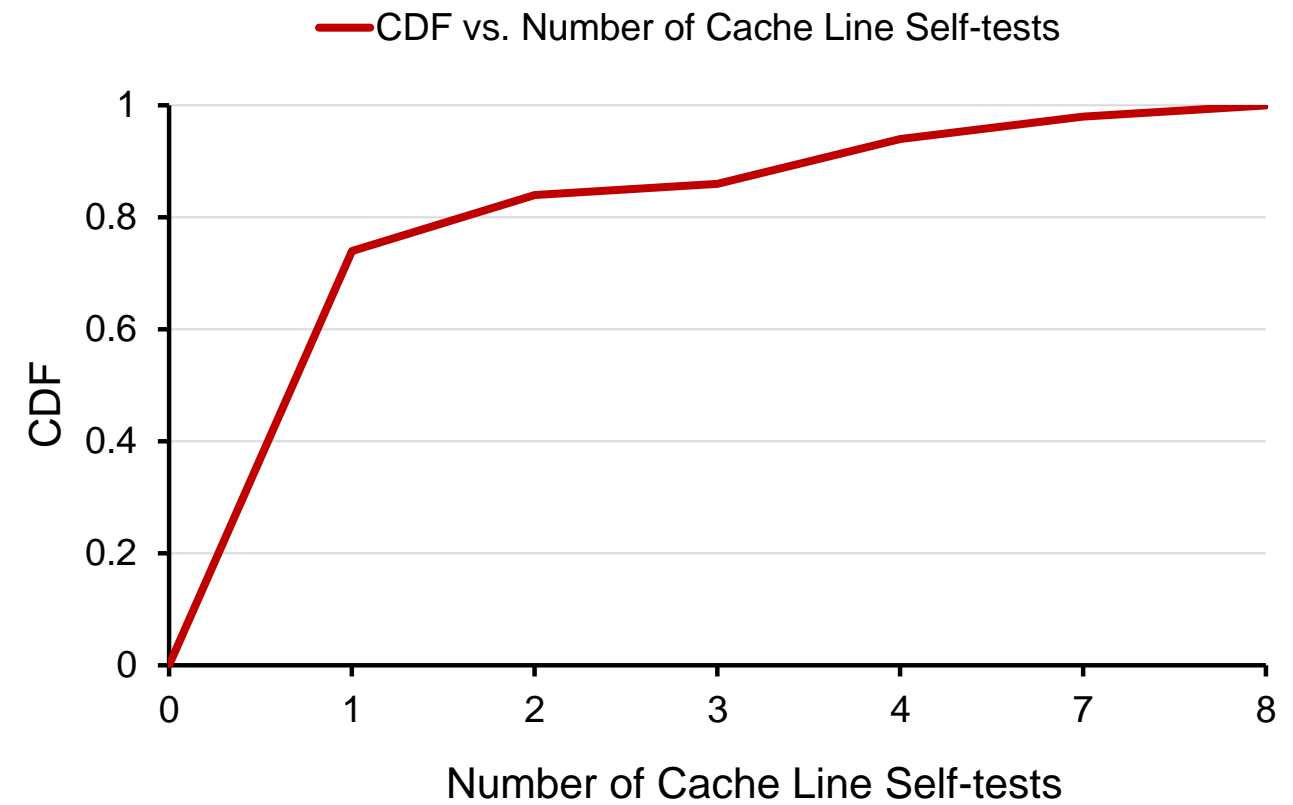
Repeatability and Performance

- Repeatability cache line errors



Repeatability and Performance

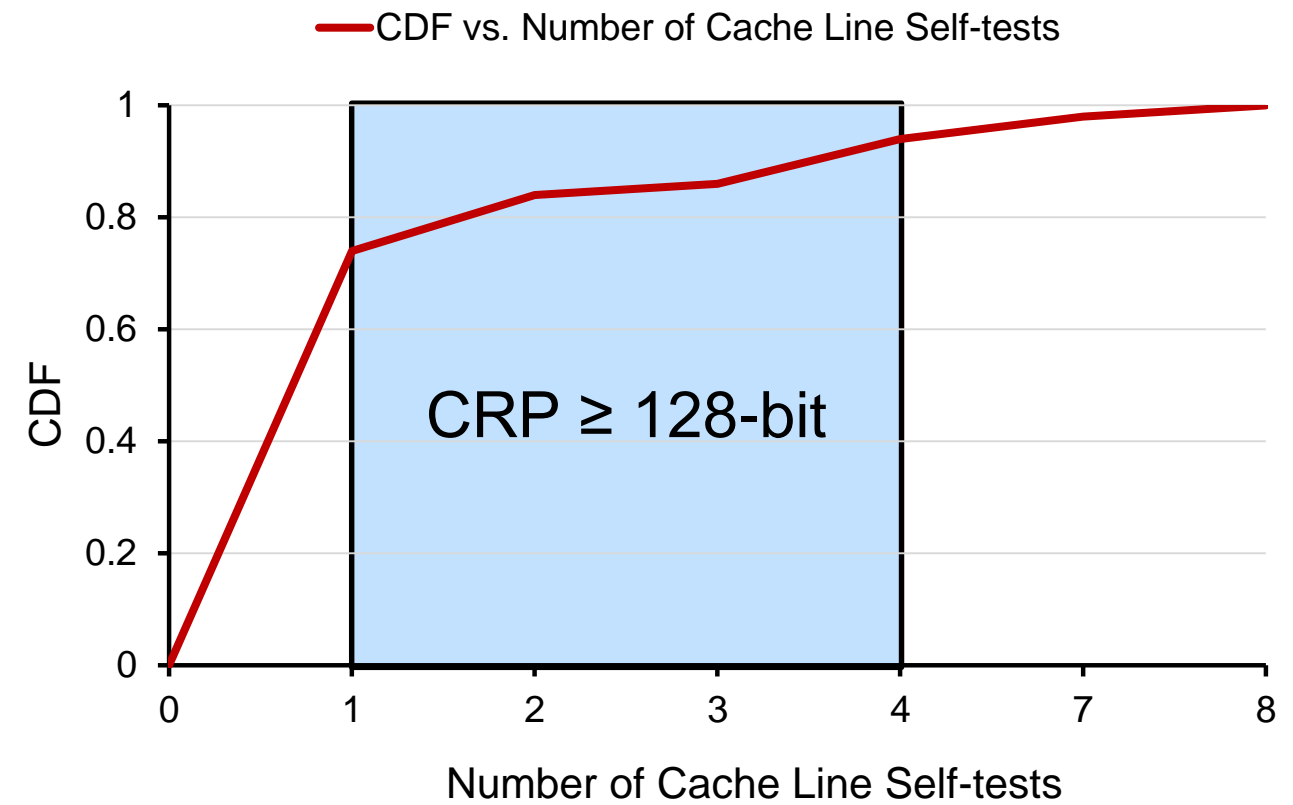
- Repeatabile cache line errors





Repeatability and Performance

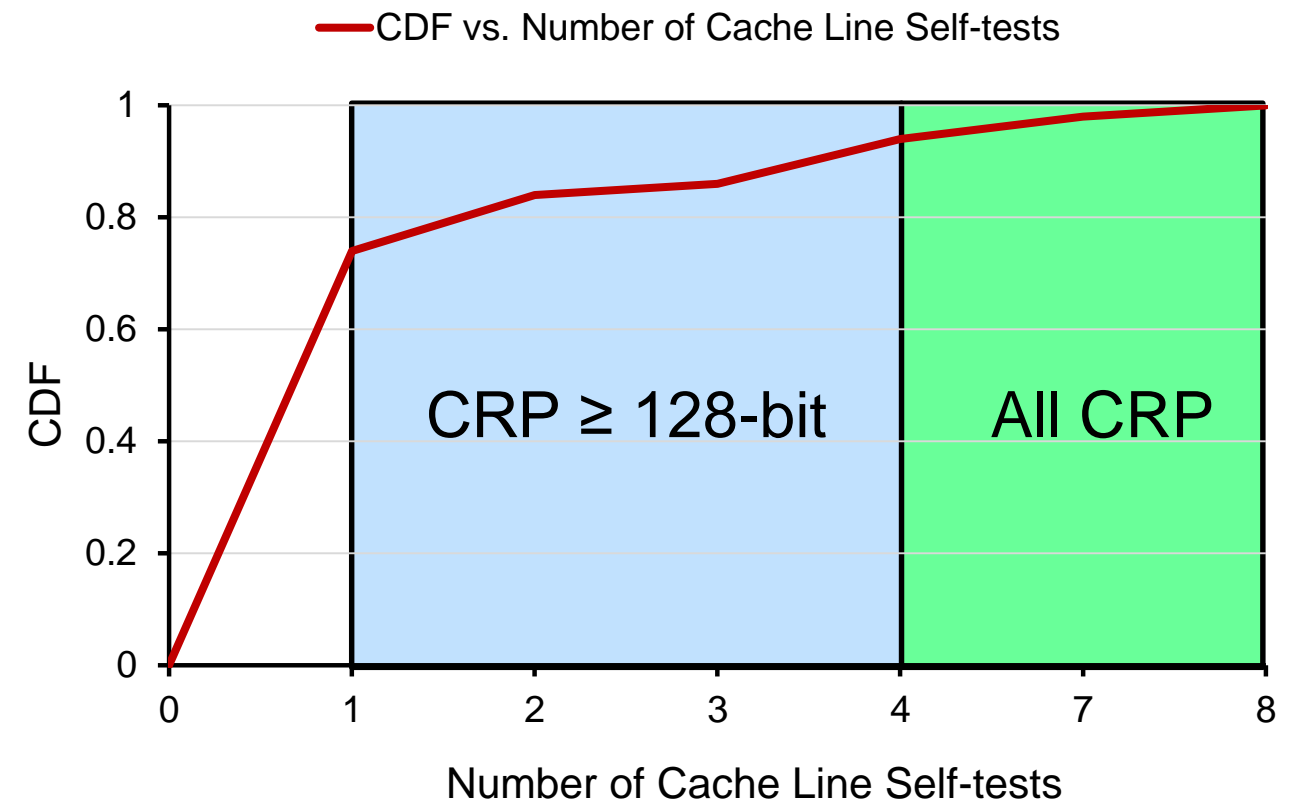
- Repeatabile cache line errors





Repeatability and Performance

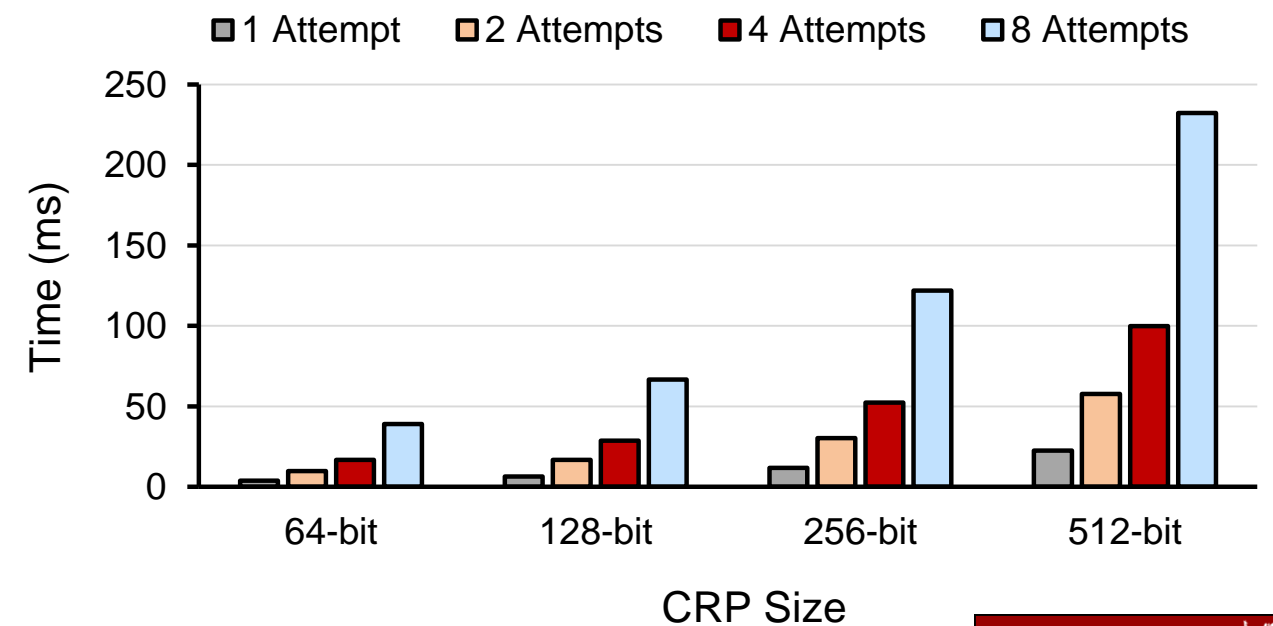
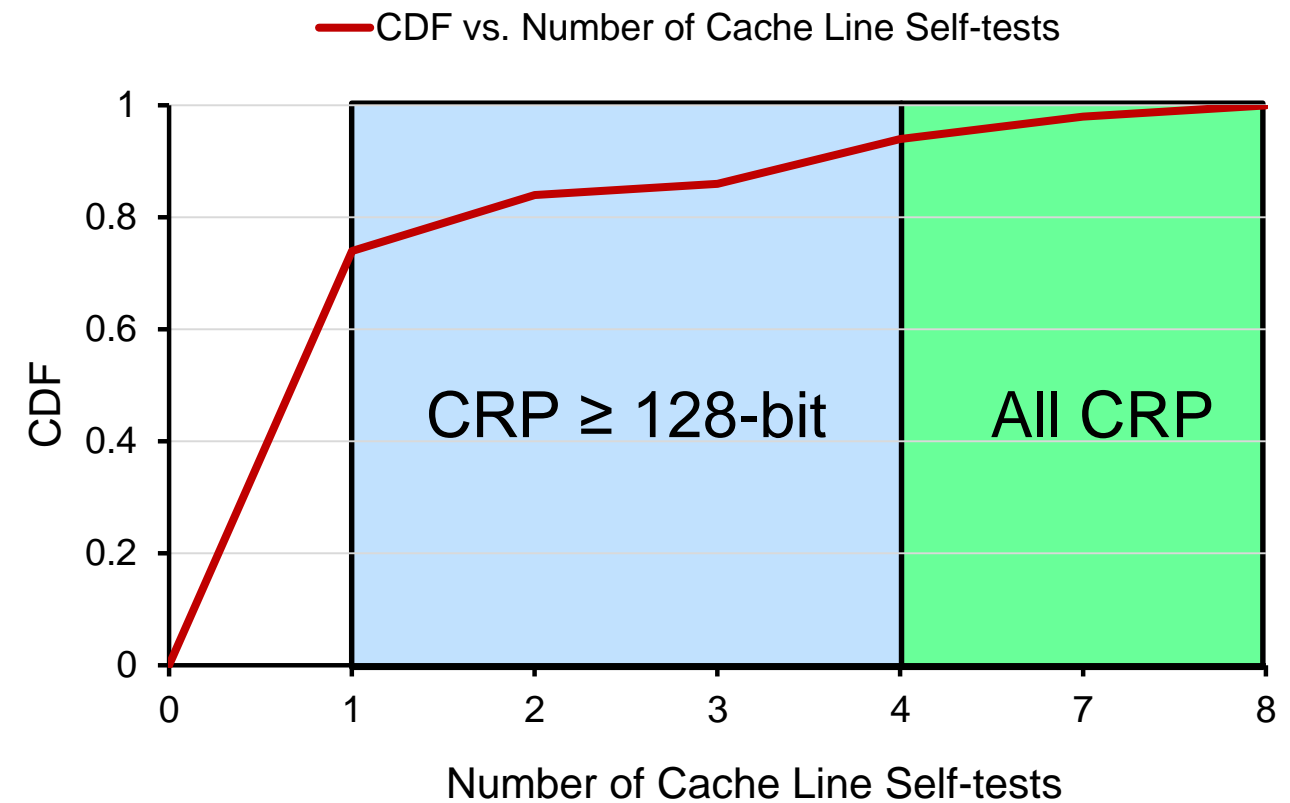
- Repeatabile cache line errors





Repeatability and Performance

- Repeatable cache line errors
- Linear increase in runtime as a function of self-test attempts

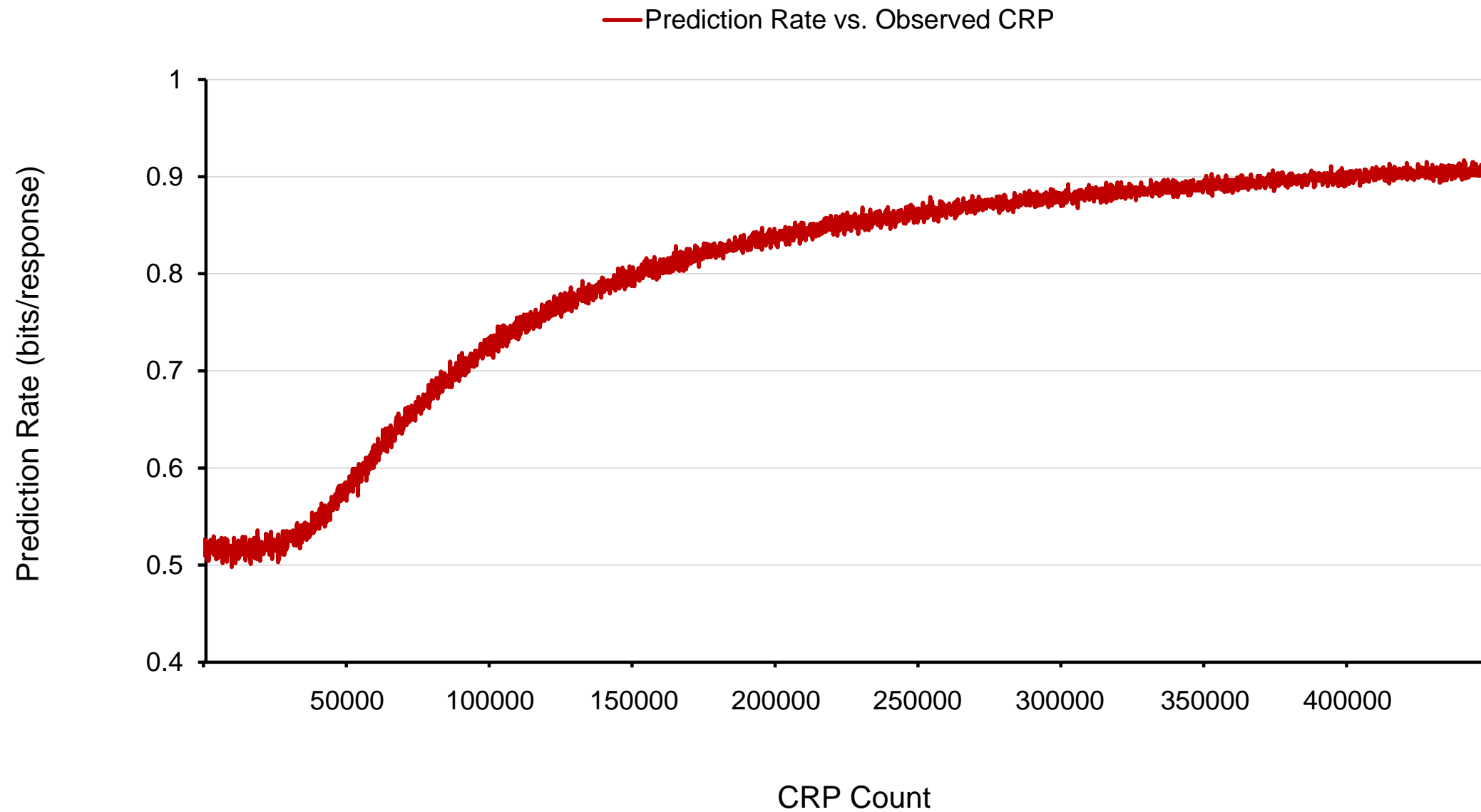




Model Building Attack Case Study

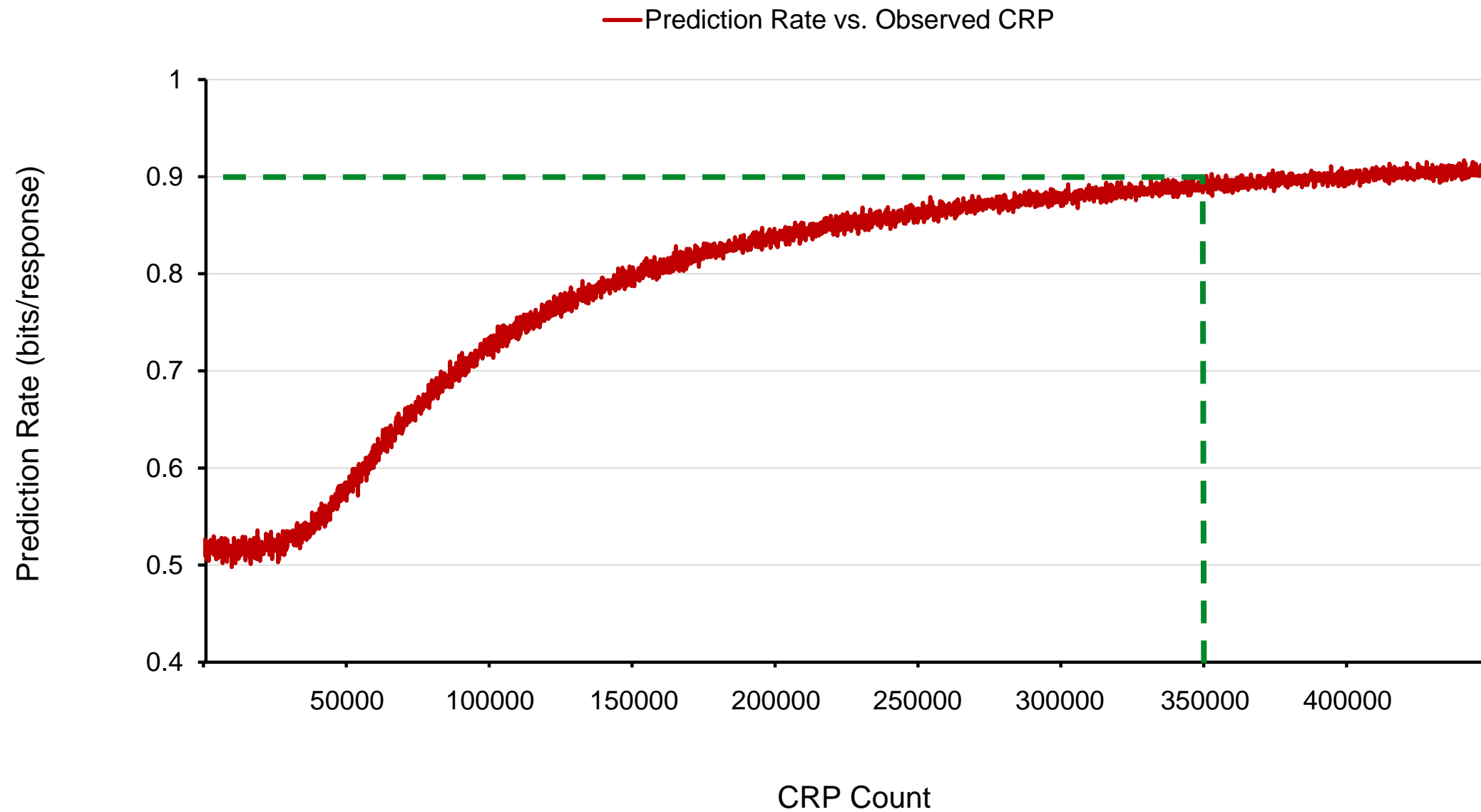


Model Building Attack Case Study



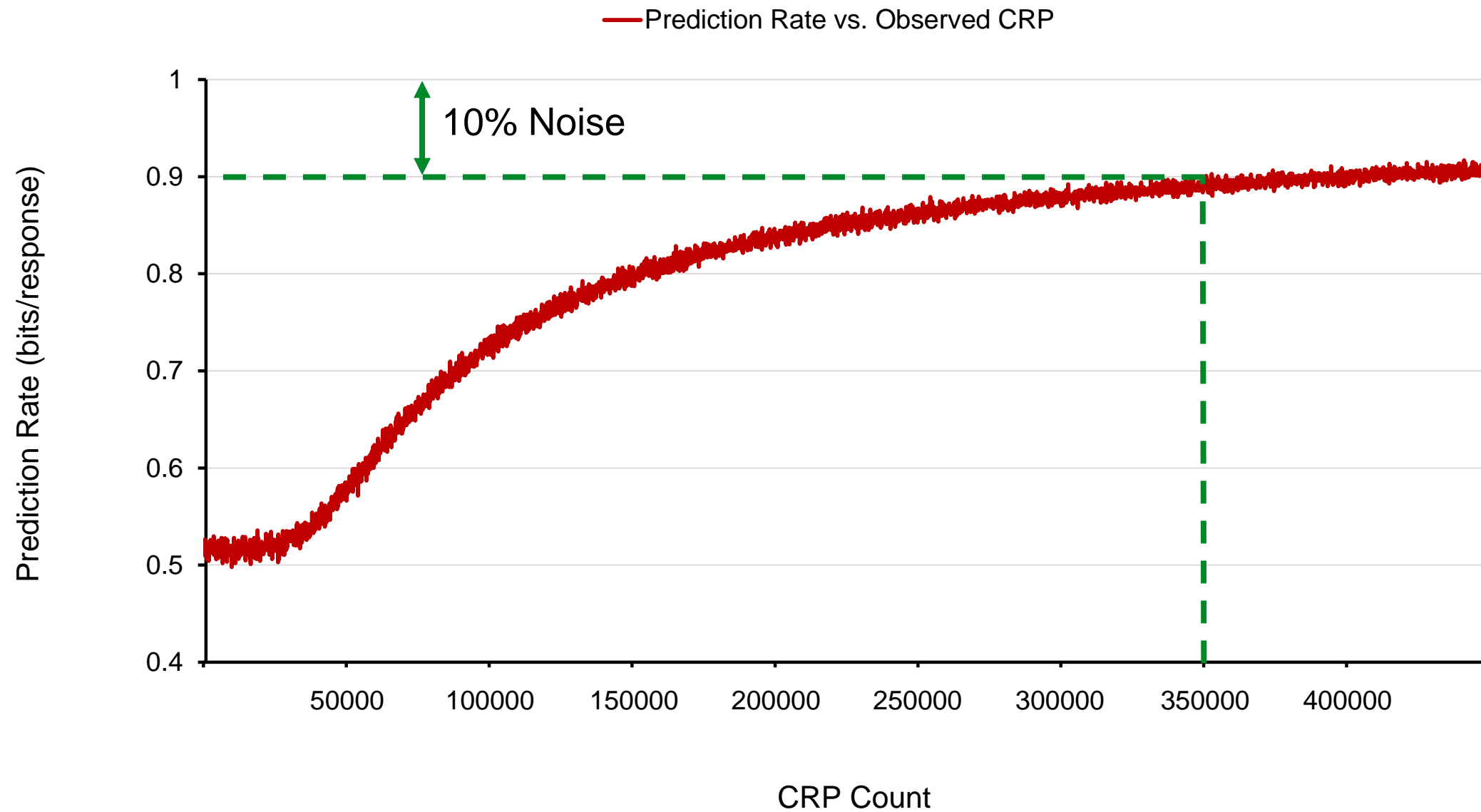


Model Building Attack Case Study



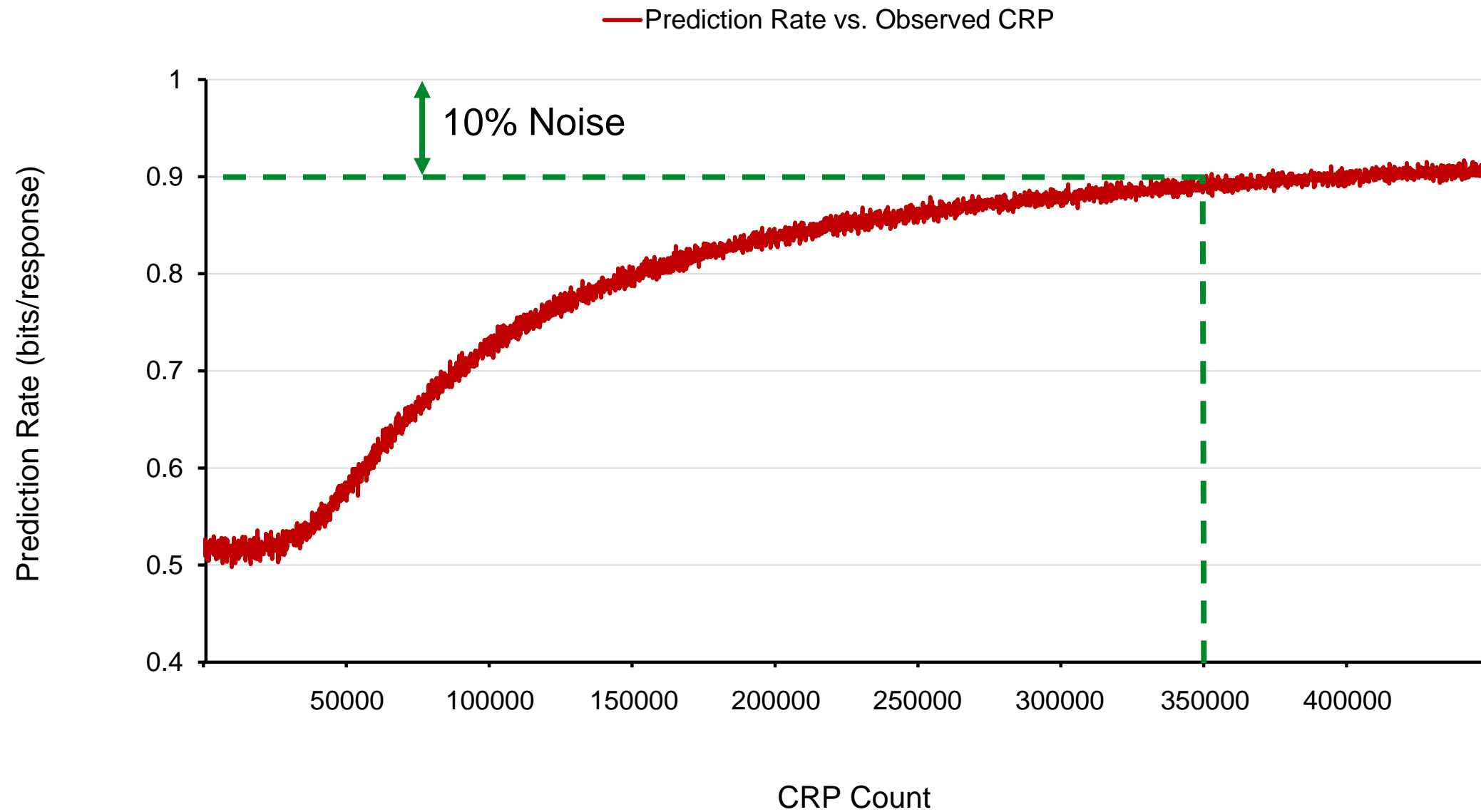


Model Building Attack Case Study





Model Building Attack Case Study



Regenerate logical error map



Conclusion

- Observe that correctable errors in caches can be used as silicon fingerprints
- Introduce a challenge-response design that can sustain large number of authentications (10 year lifetime)
- Demonstrate robustness of technique to noise (up to 142%)
- Realize a proof-of-concept to show system is practical



Thank you!
Questions?

Authenticache: Harnessing Cache ECC for System Authentication

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